

# Lecture 4: CMOS Inverter Fabrication (and Layout)



*Based on material prepared by prof. Visvesh S. Sathe*

# Acknowledgements

All class materials (lectures, assignments, etc.) based on material prepared by Prof. Visvesh S. Sathe, and reproduced with his permission

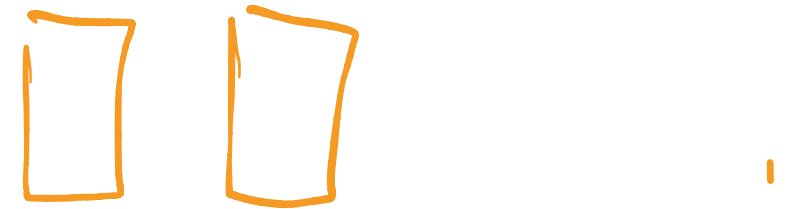


Visvesh S. Sathe  
Associate Professor  
Georgia Institute of Technology  
<https://psylab.ece.uw.edu>

UW (2013-2022)  
GaTech (2022-present)

# The Design Process

- High-level design → Schematic → **Layout** → **Fabrication**
- Layout (or Mask layout) is the exchange format to specify exactly how you want each transistor in your design to look
- CMOS inverter layout (step by step) , and how it determines the fabrication process
- **Design Rule Checks (DRCs)** and their importance
  - Metal-metal
  - Via enclosure
  - Poly past active
  - Active within nwell, away from nwell
  - Min width rules/Min area rules
  - Minimum overlap
- Some aspects of modern fabrication process tech.



# CMOS Inverter: Logic to Silicon View

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- Schematic is converted to “mask-layout” for fabrication
  - Actual 2D geometrical description of how the inverter is to be fabricated
  - Polygons of different “layers” describe construction of the inverter
  - “Mask” term due to use of these shapes as masks during photolithography (and eventually etch) to define the target shapes in each layer
- Starting point: Clean silicon wafer with an epitaxially-grown doped, P-type substrate

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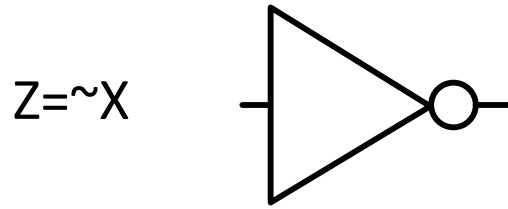
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—————→ Production

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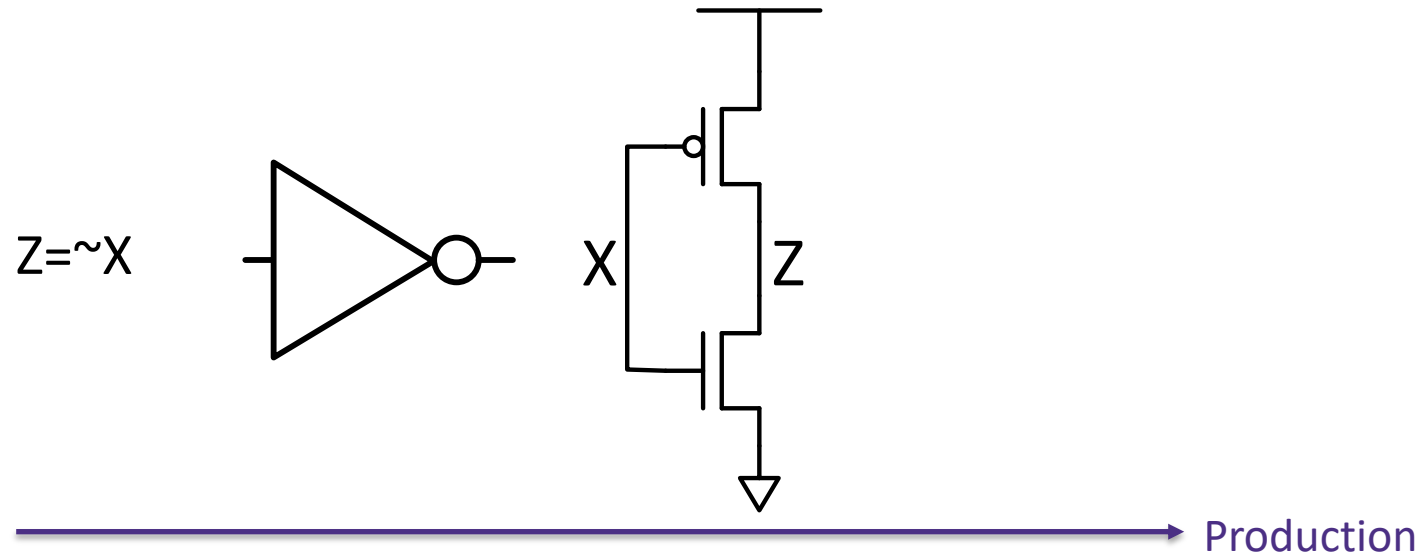
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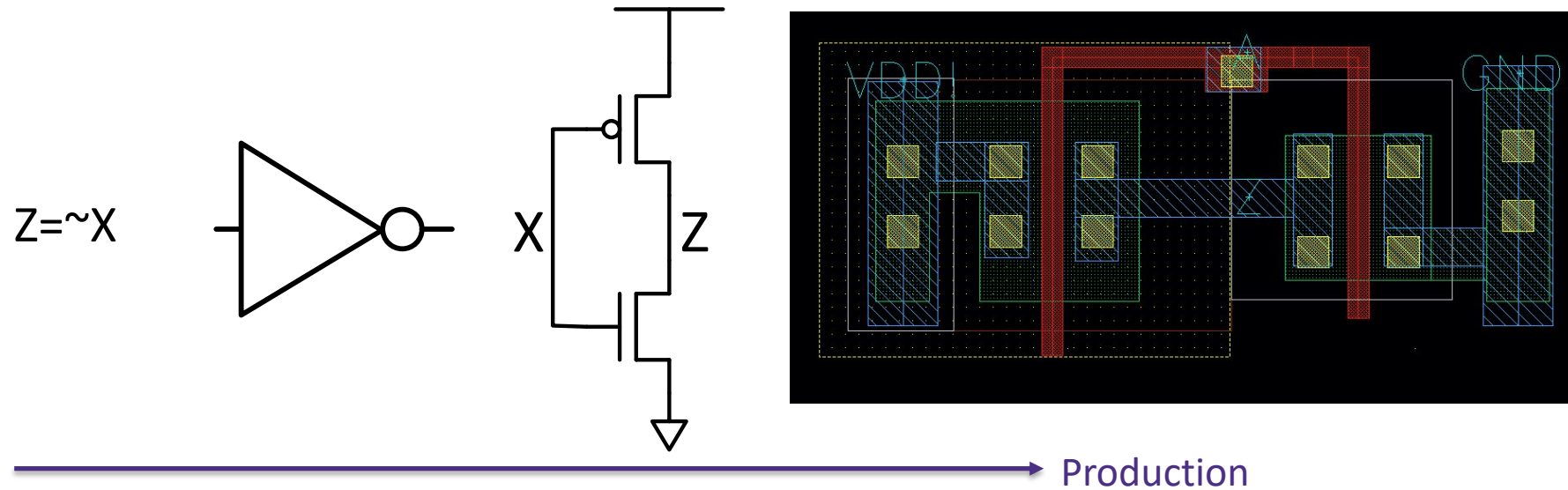
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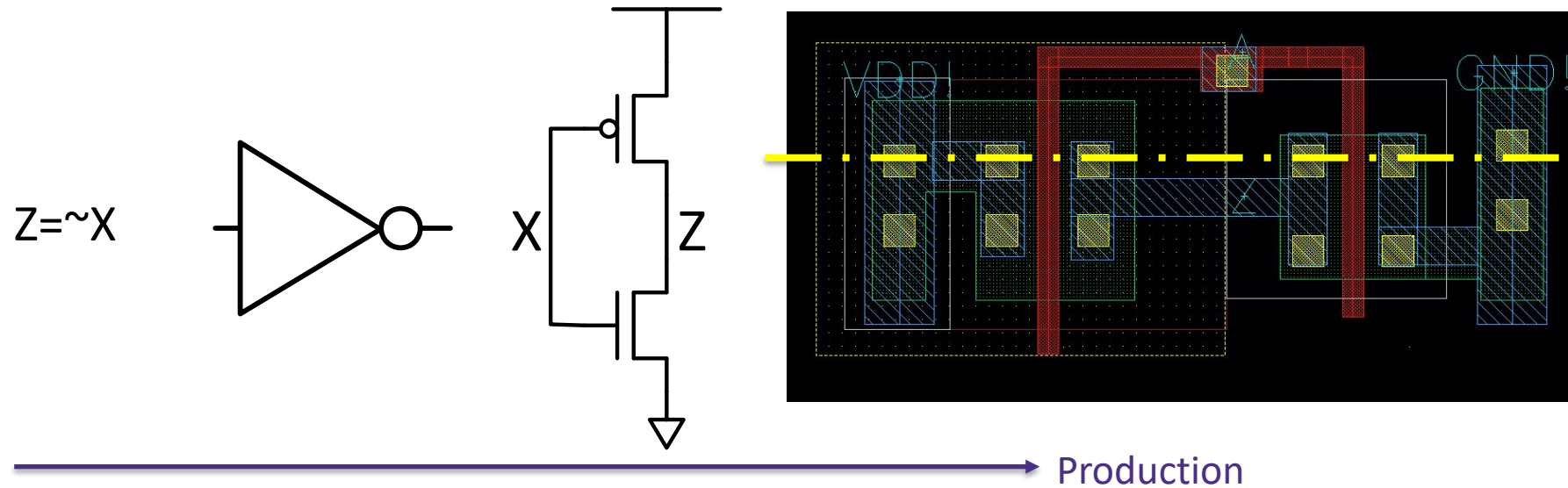


# CMOS Inverter: Logic to Silicon View

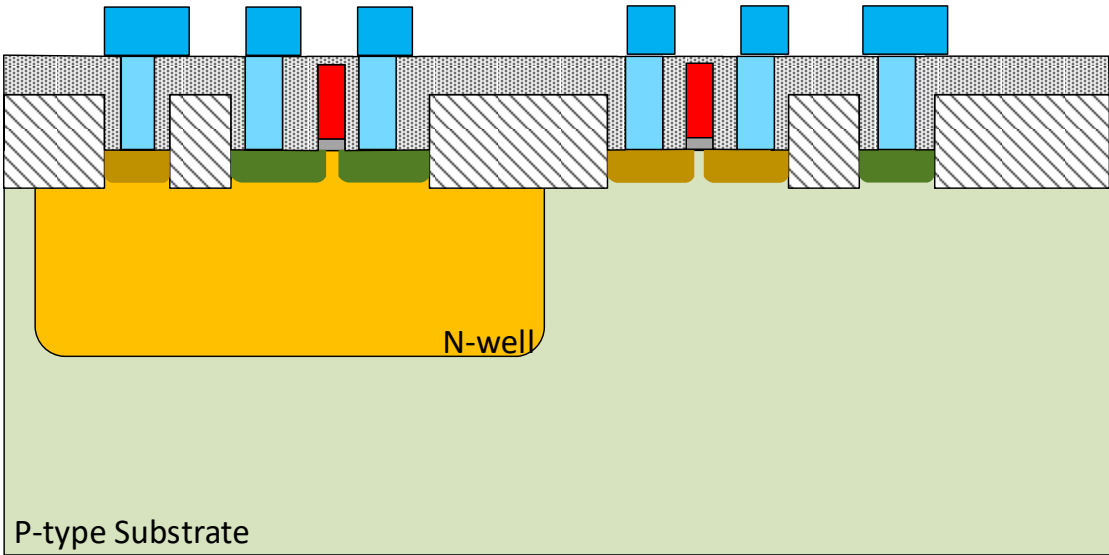


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# CMOS Inverter: Logic to Silicon View

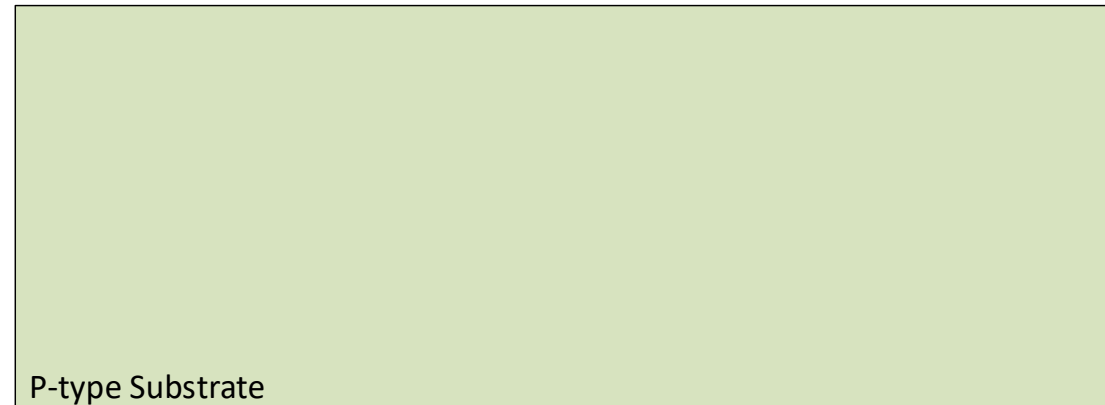


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## 1.1: Create *Nwell* region

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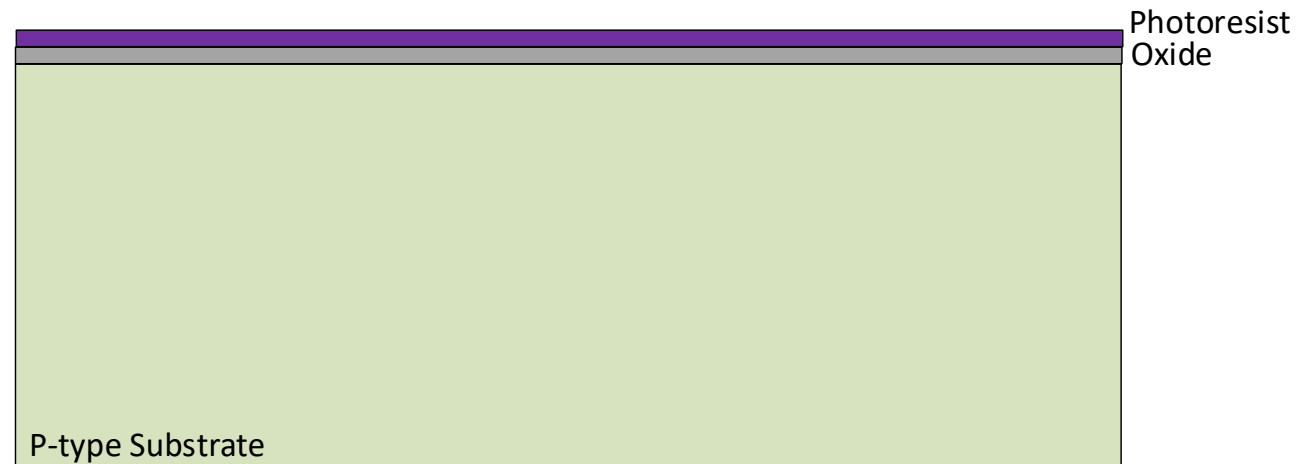


## 1.2: Create *Nwell* region



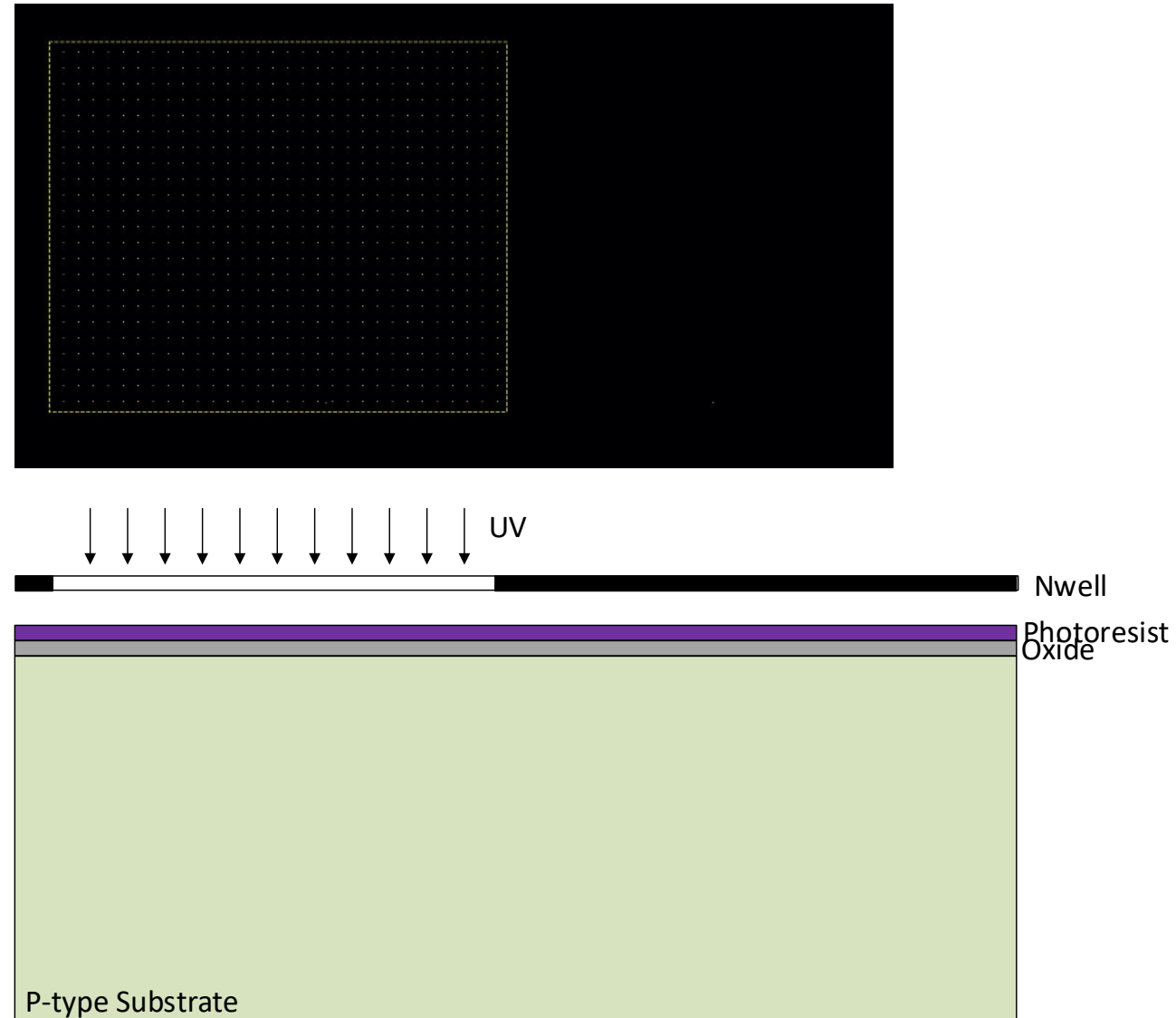
- Grow oxide-layer to serve as a barrier

## 1.3: Create *Nwell* region



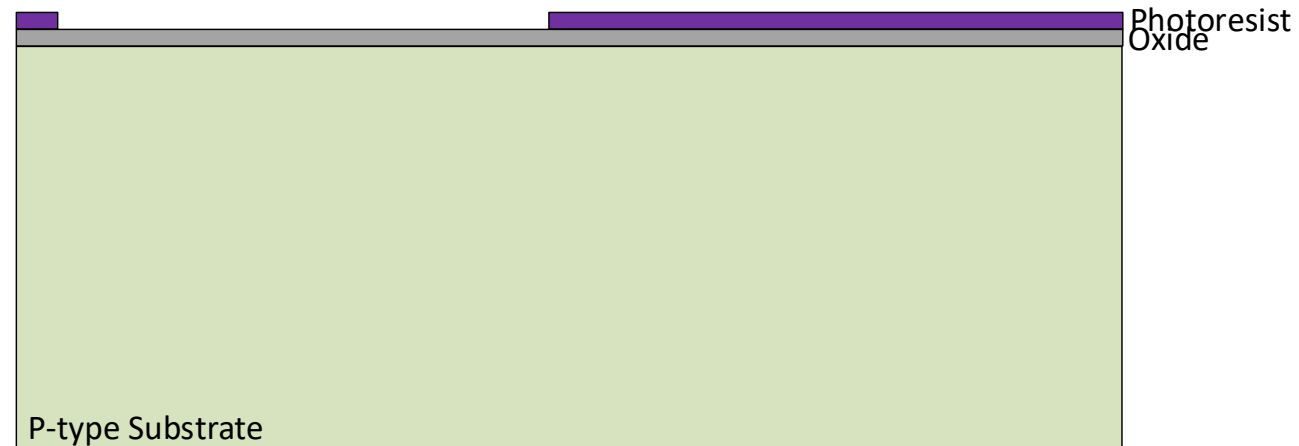
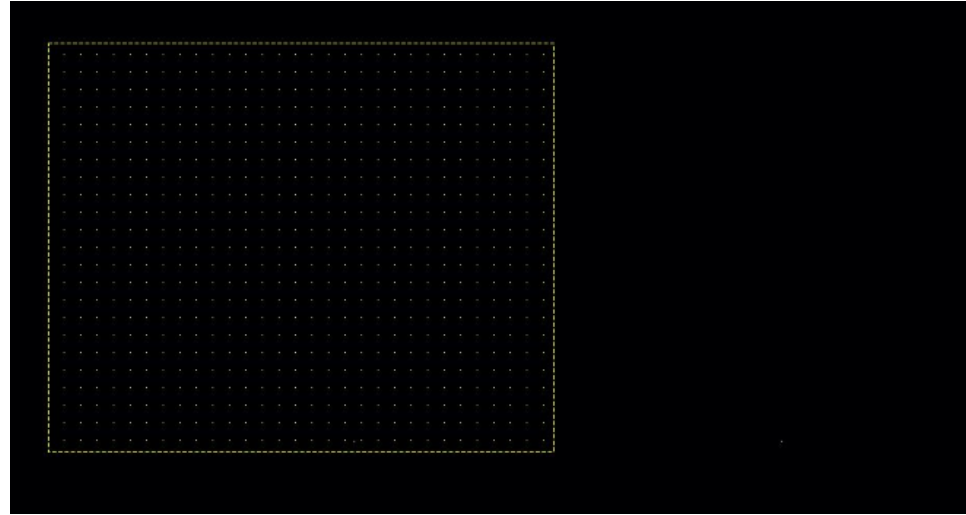
- Deposit photoresist

## 1.4: Create *Nwell* region



- Use N-Well Mask to allow light to selectively soften photoresist

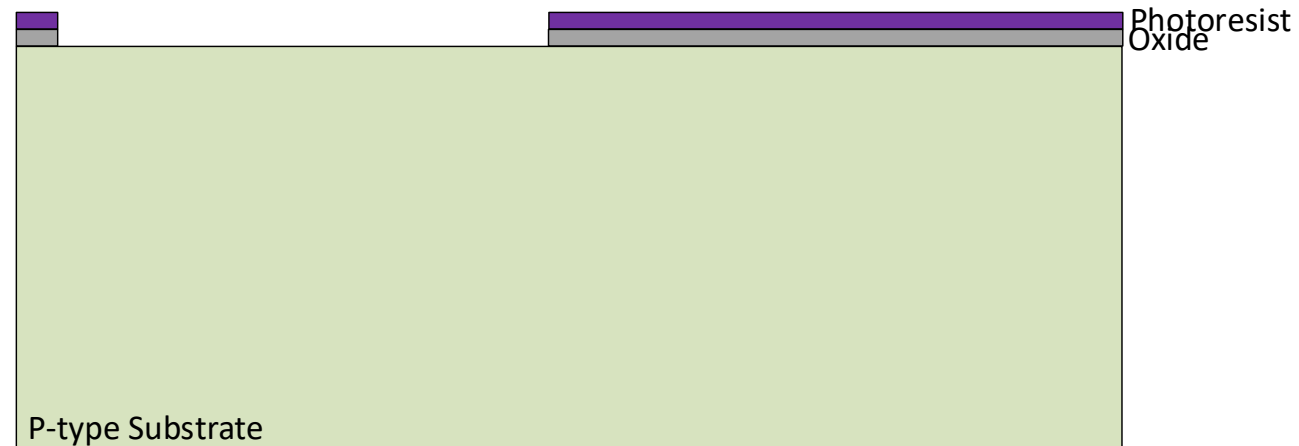
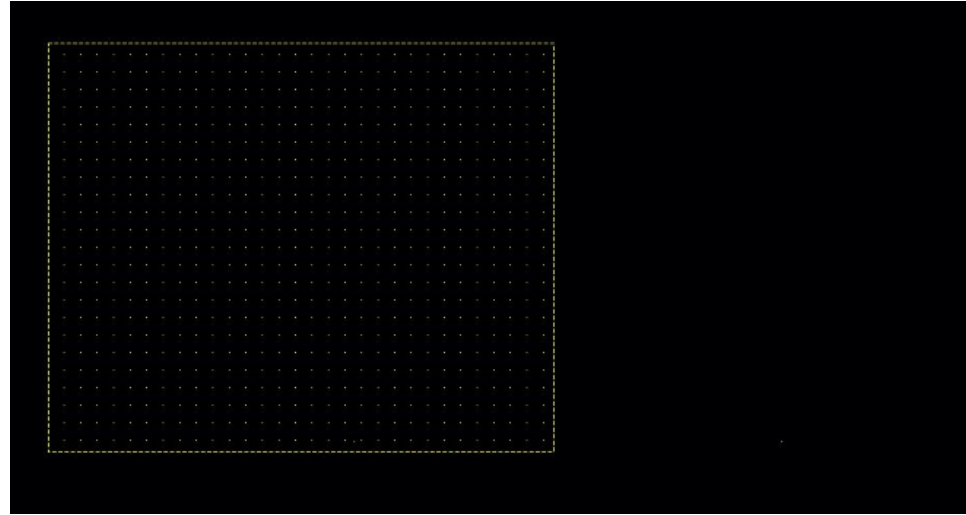
## 1.5: Create *Nwell* region



- Wash away softened photoresist

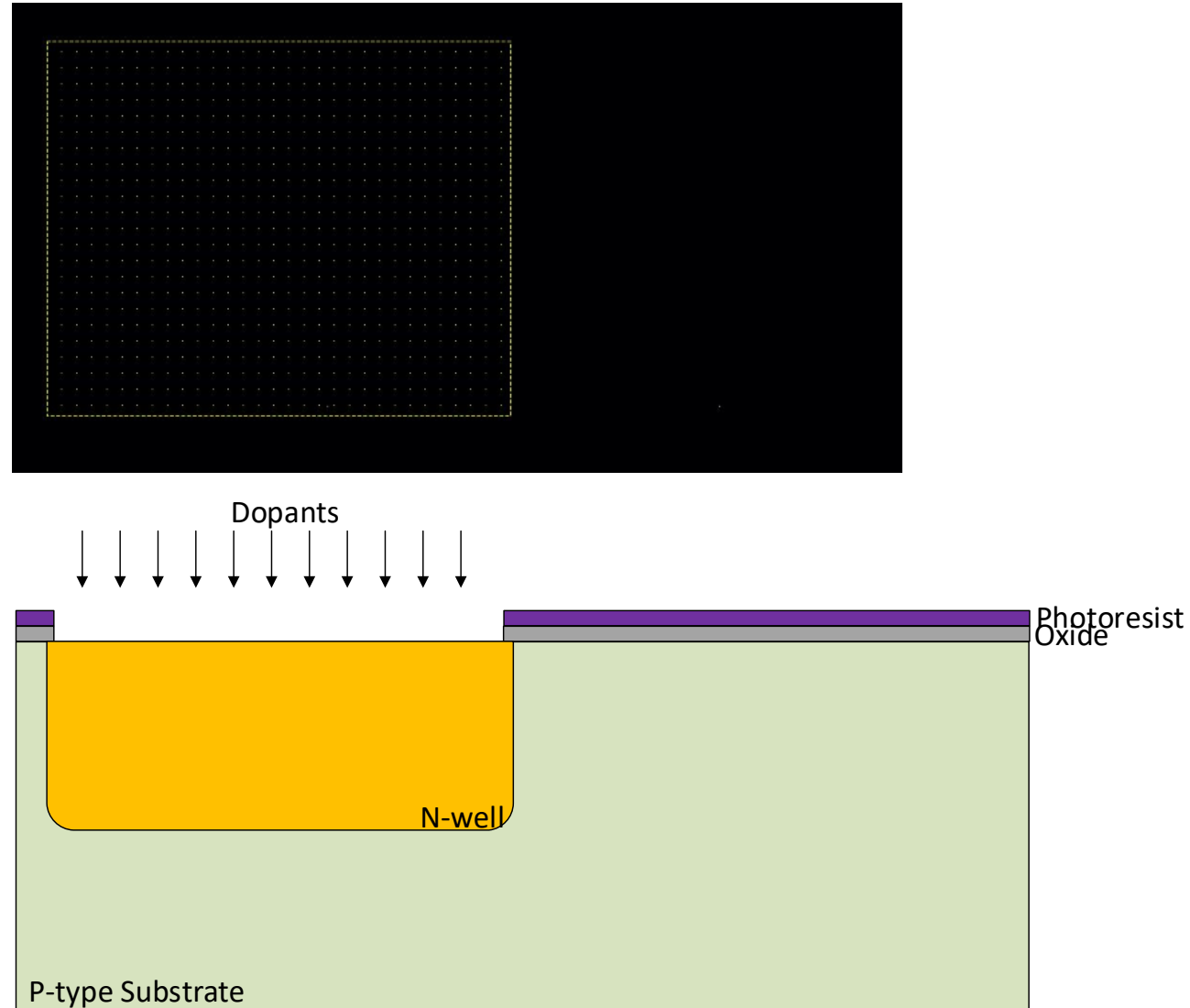


## 1.6: Create *Nwell* region



- Etch away  $\text{SiO}_2$

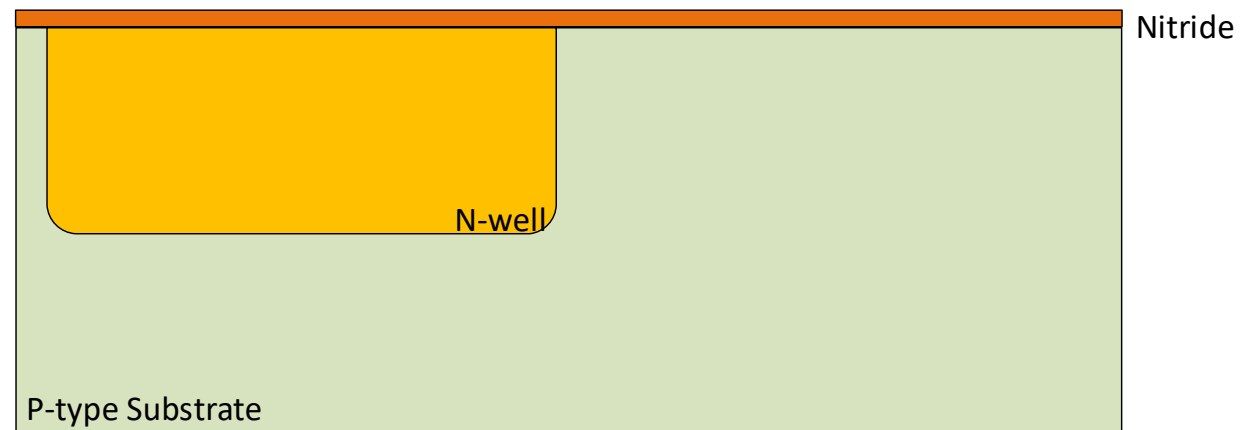
## 1.7: Create *Nwell* region



- Deposit N-type dopants and anneal for formation of N-well

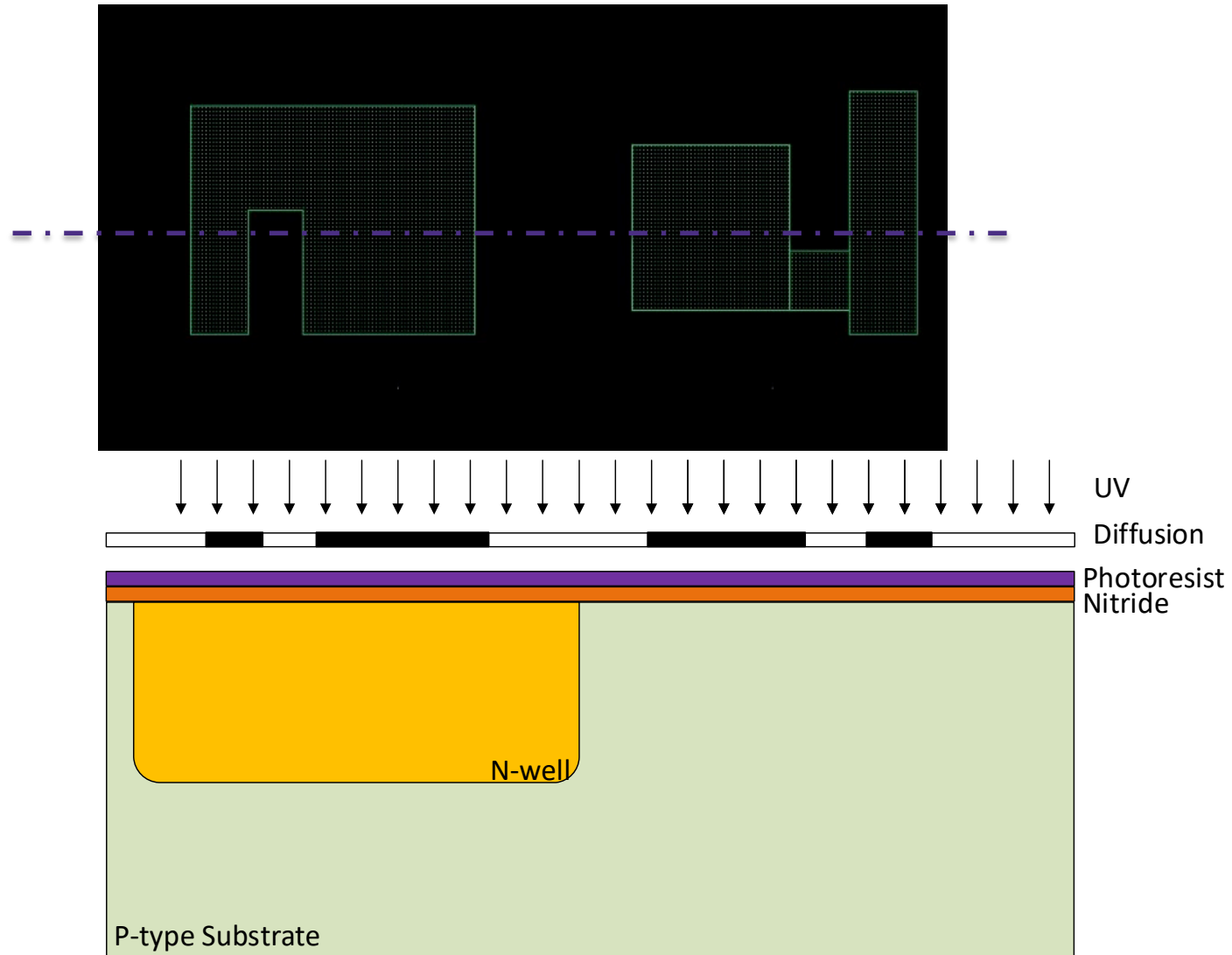
## 2.1: Grow Field Oxide Outside Diffusion

- Grow field-oxide over regions outside transistor and contact areas



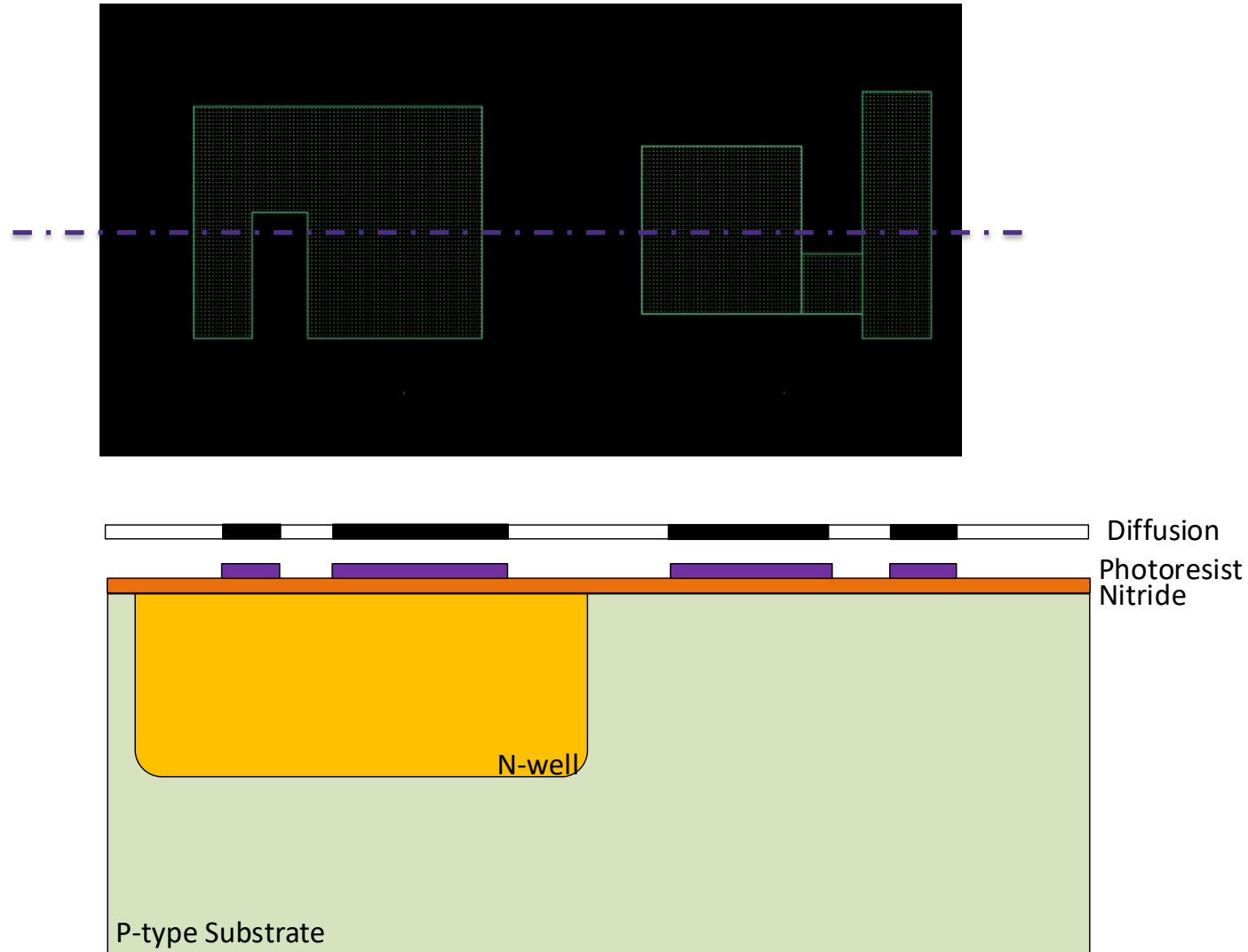
- First form a  $\text{Si}_3\text{N}_4$  layer over silicon (prevent oxidation)

## 2.2: Grow Field Oxide Outside Diffusion



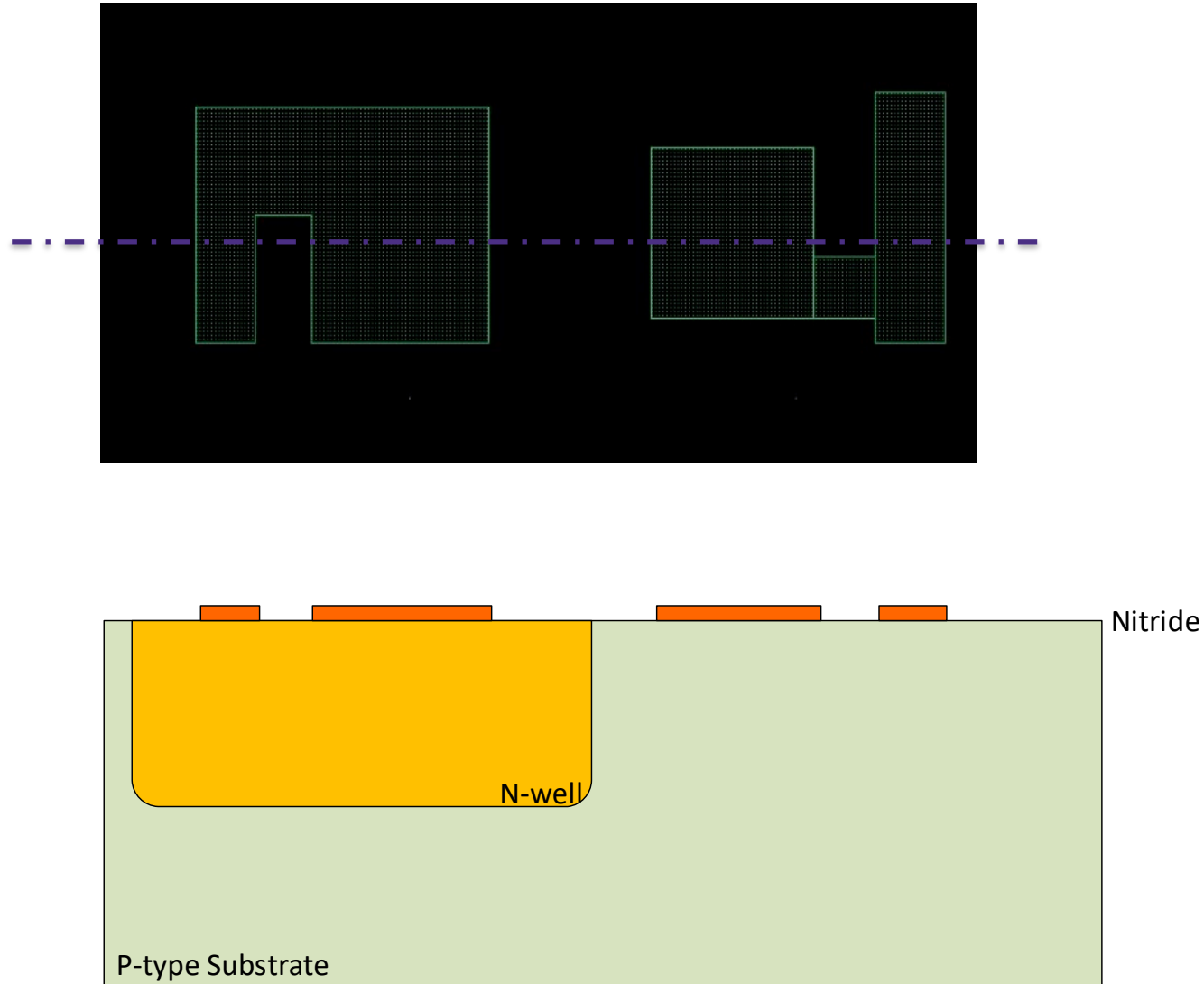
- Use OD\* mask to selectively soften deposited photoresist

## 2.3: Grow Field Oxide Outside Diffusion



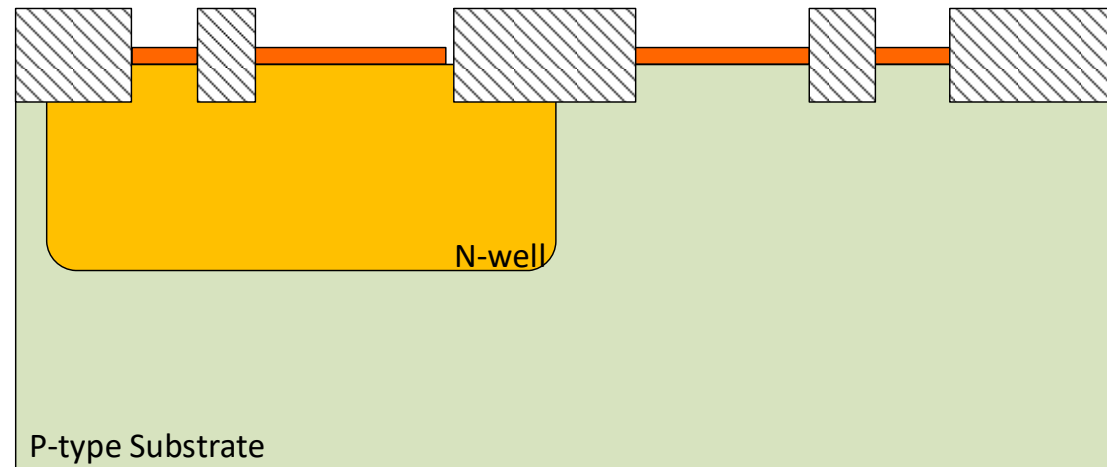
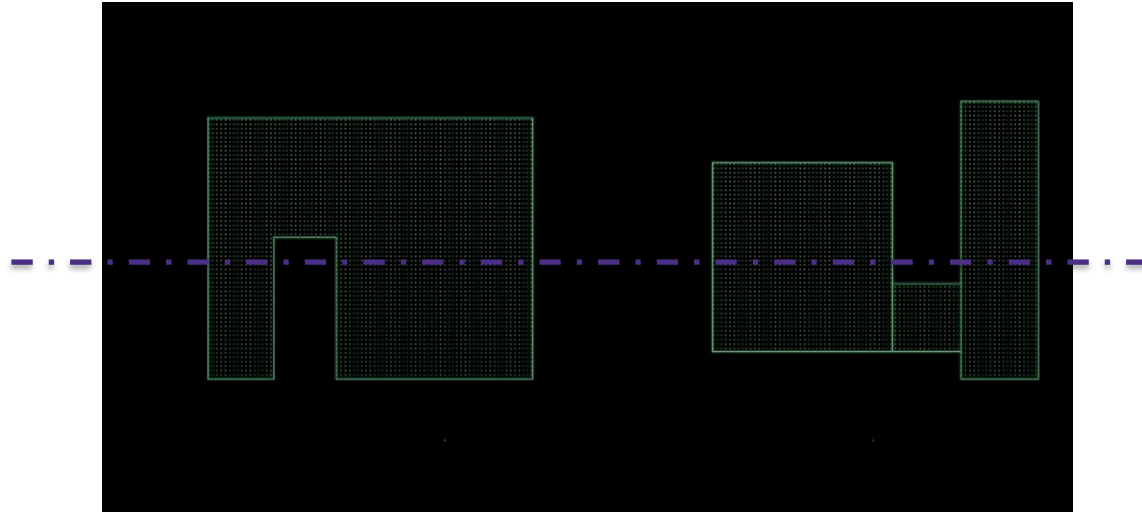
- Wash off softened photoresist

## 2.4: Grow Field Oxide Outside Diffusion



- *Piranha* etch photoresist

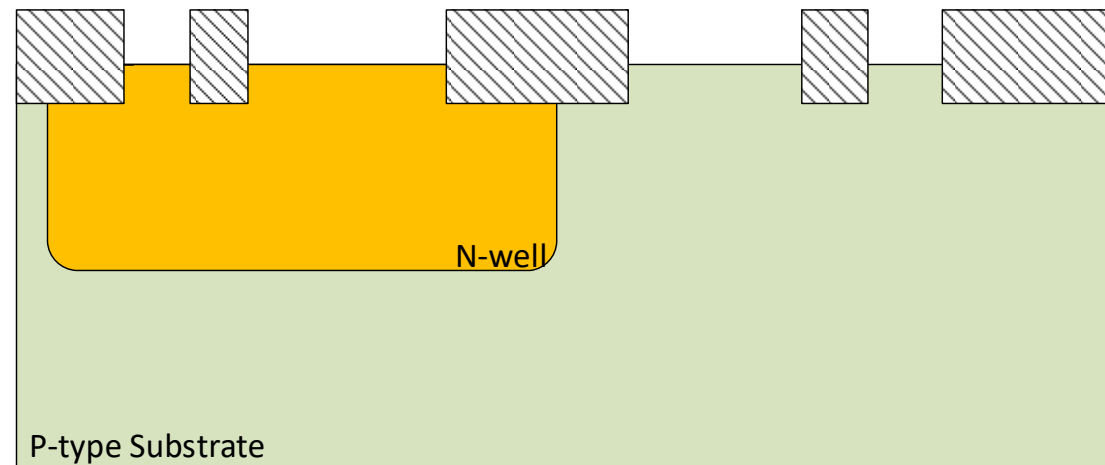
## 2.5: Grow Field Oxide Outside Diffusion



- Grow field-oxide over regions outside transistor and contact areas

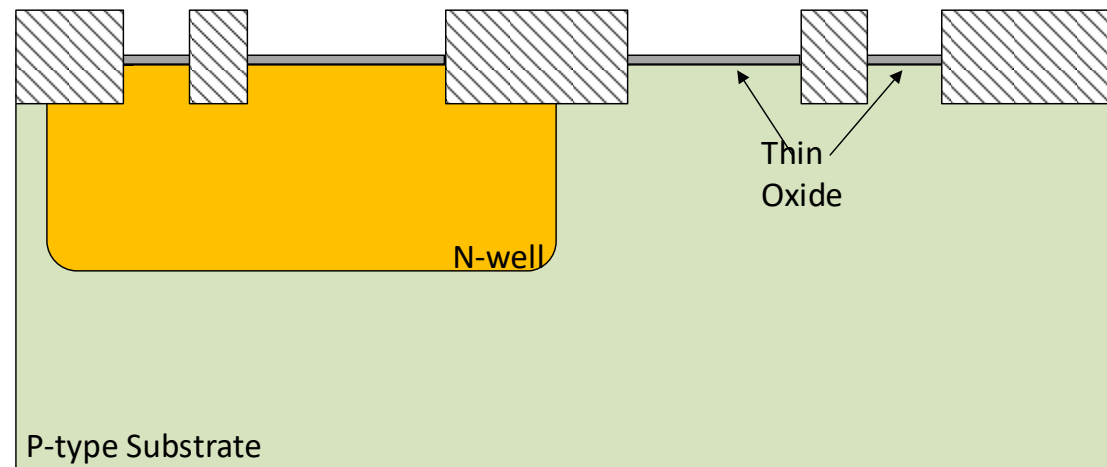
### 3:Build Polysilicon Gate

- Build the gate using polycrystalline silicon (or Polysilicon, or poly)





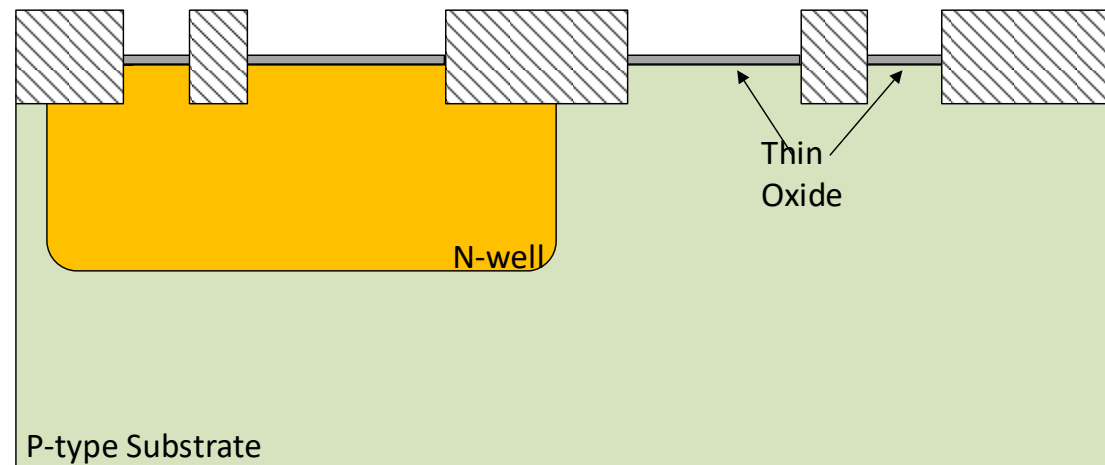
## 3.1: Build Polysilicon Gate



- Grow gate-oxide

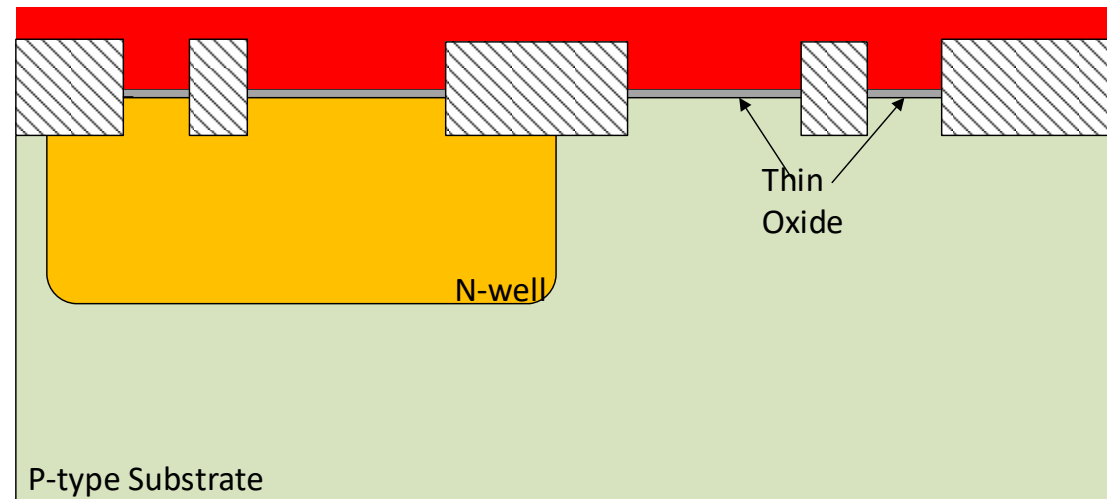
## 3.1: Build Polysilicon Gate

Great, but why do I  
**need** field oxide in  
the first place??!



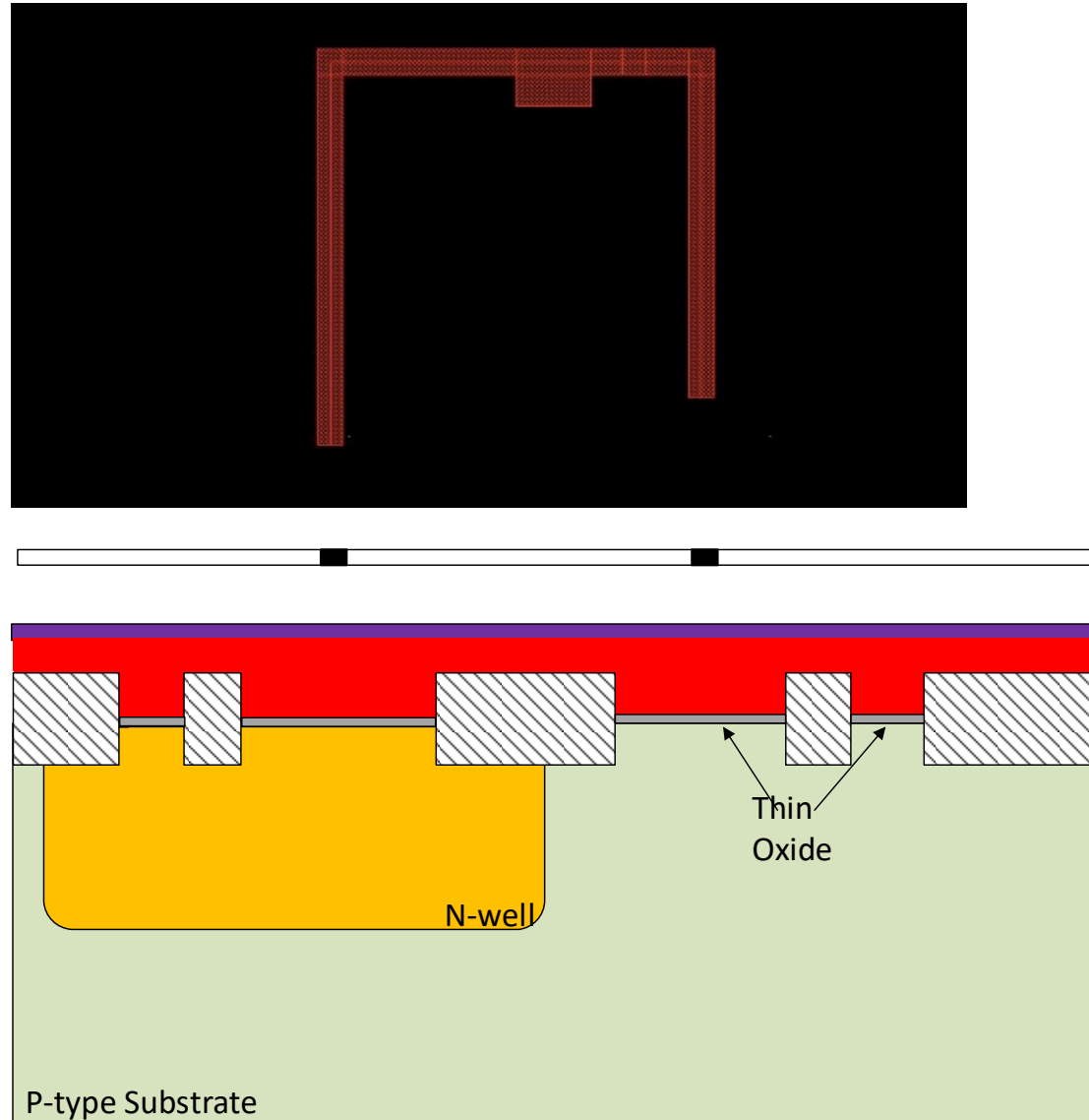
- Grow gate-oxide

## 3.2: Build Polysilicon Gate



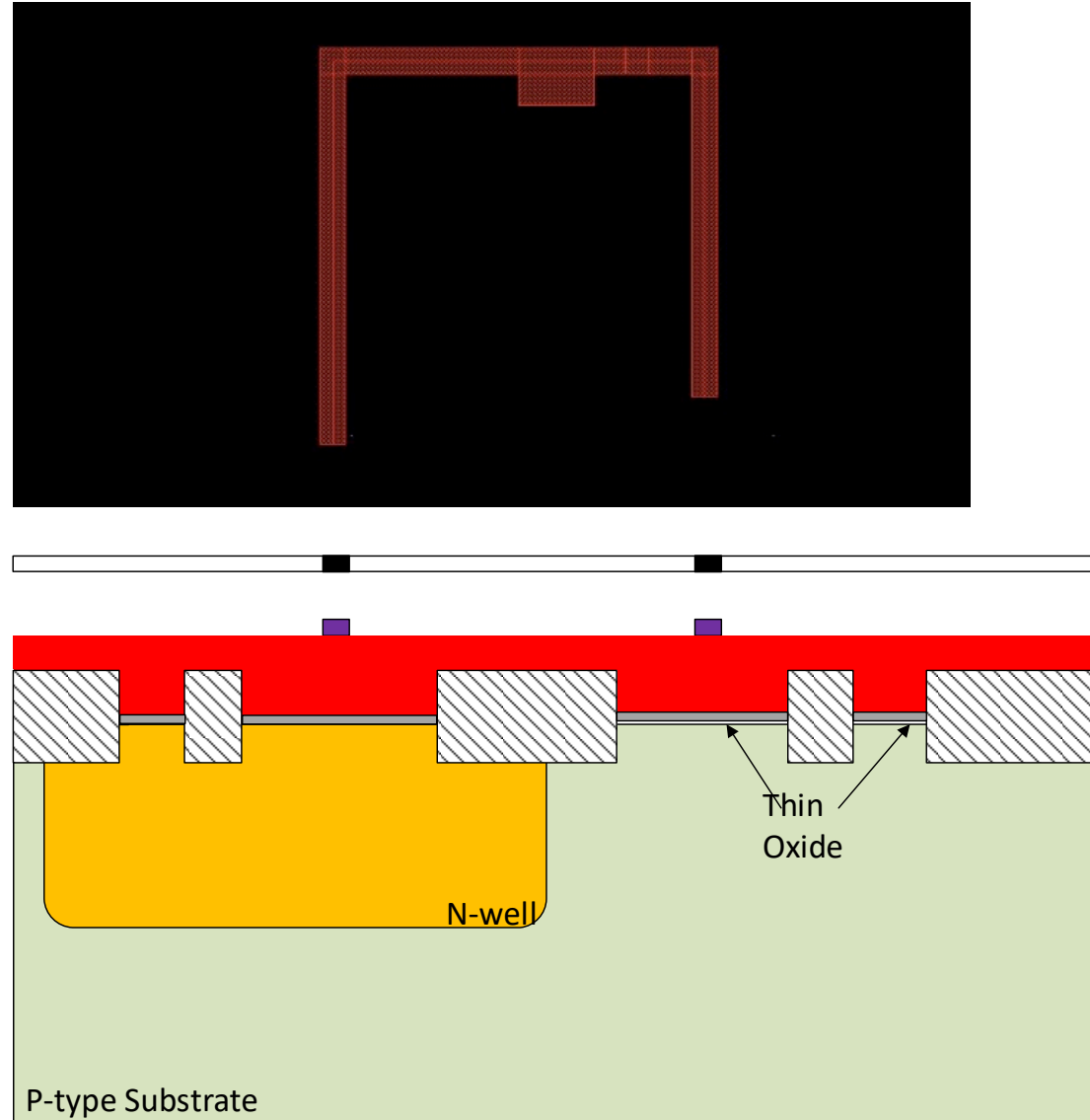
- Deposit Poly

## 3.3: Build Polysilicon Gate



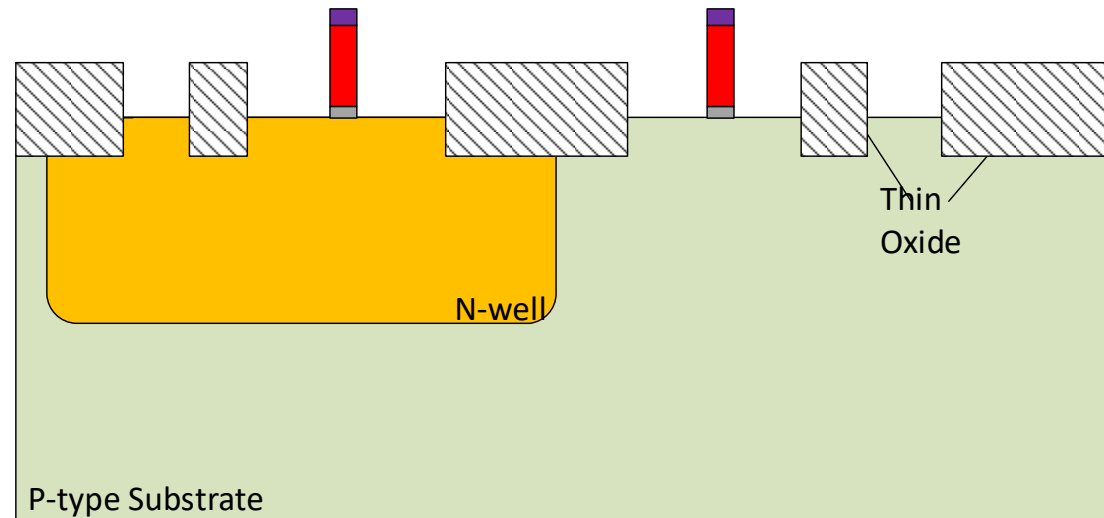
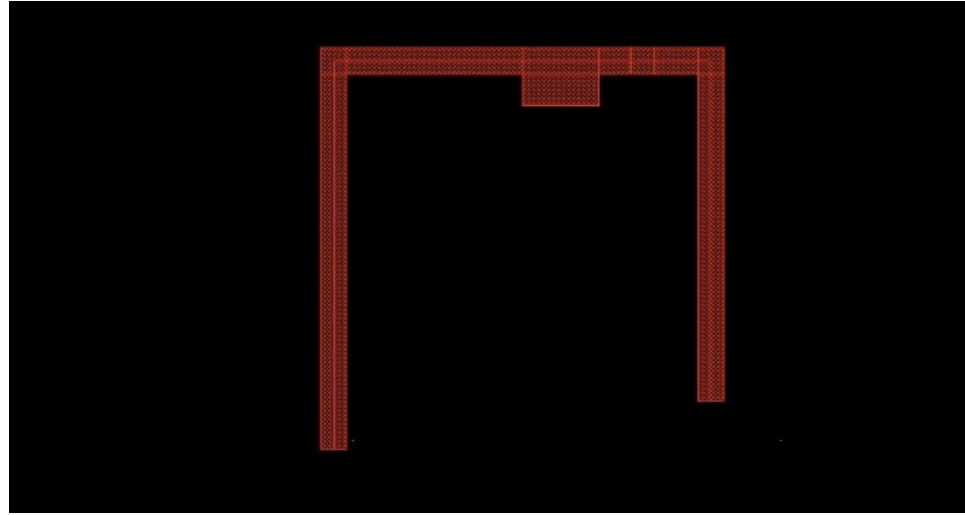
- Develop photoresist using PO mask

## 3.4: Build Polysilicon Gate



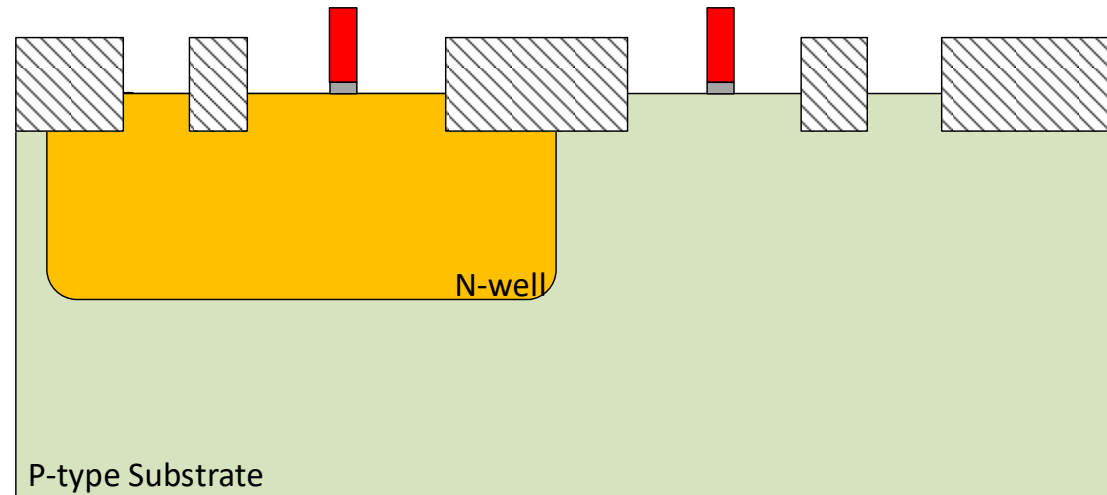
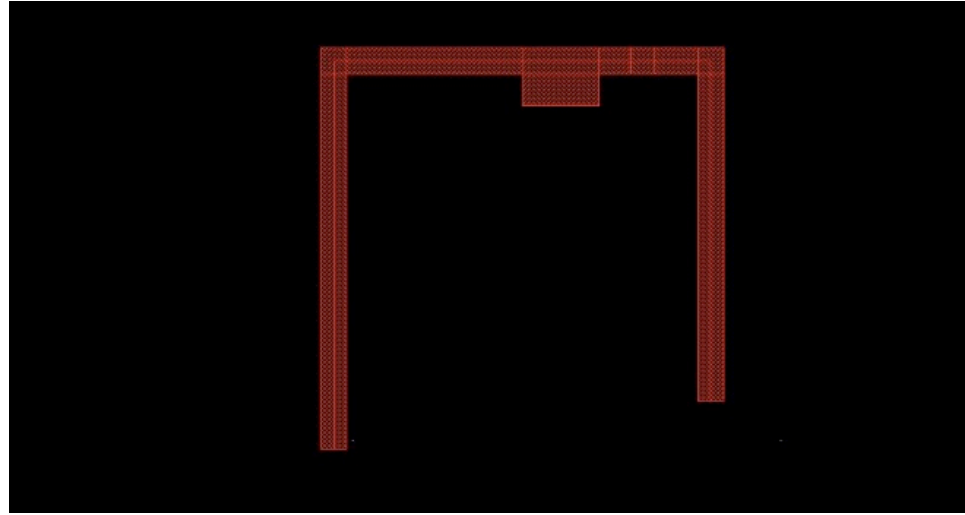
- Etch away softened photoresist

## 3.5: Build Polysilicon Gate



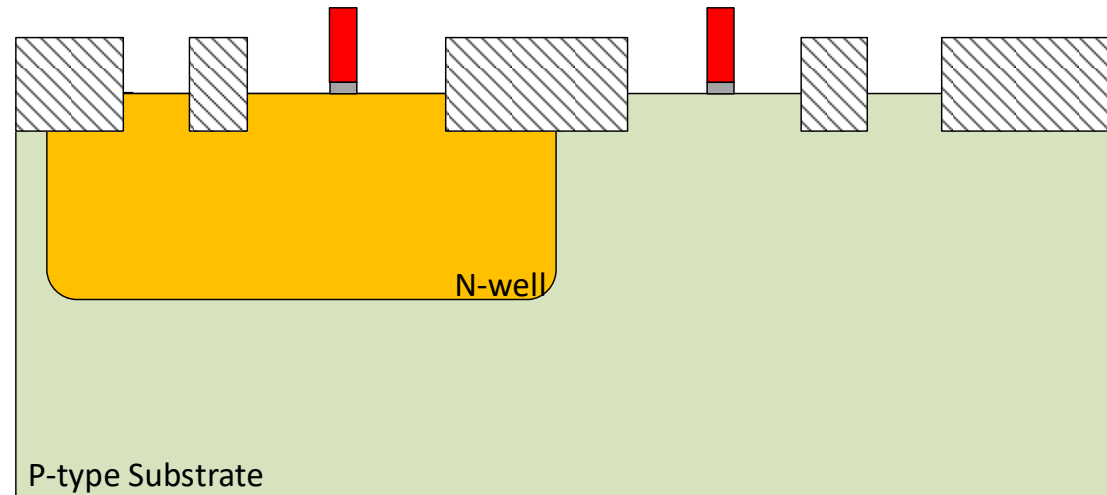
- Etch away softened photoresist

## 3.6: Build Polysilicon Gate



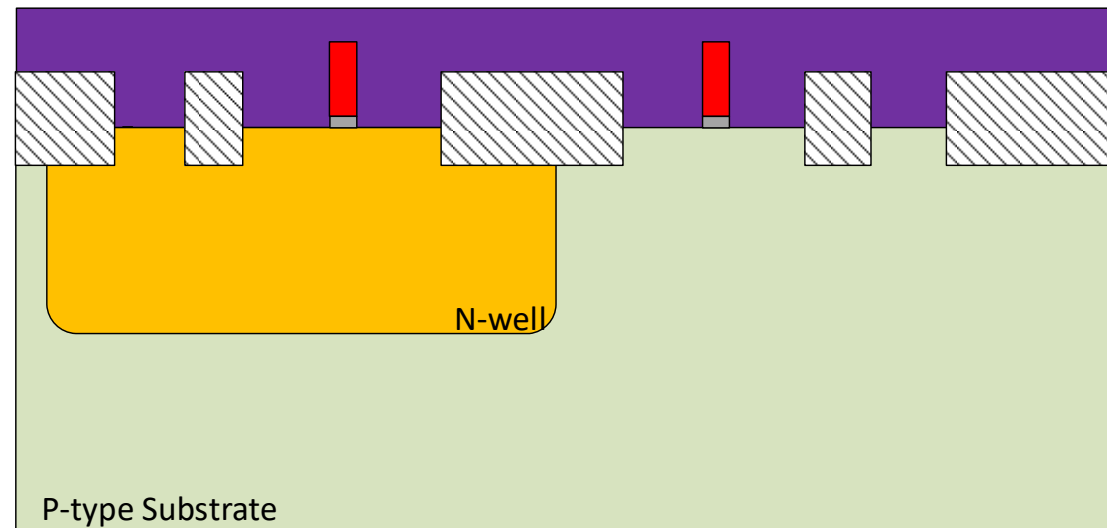
- Etch away exposed polysilicon

## 4:Build PMOS, Substrate Contact



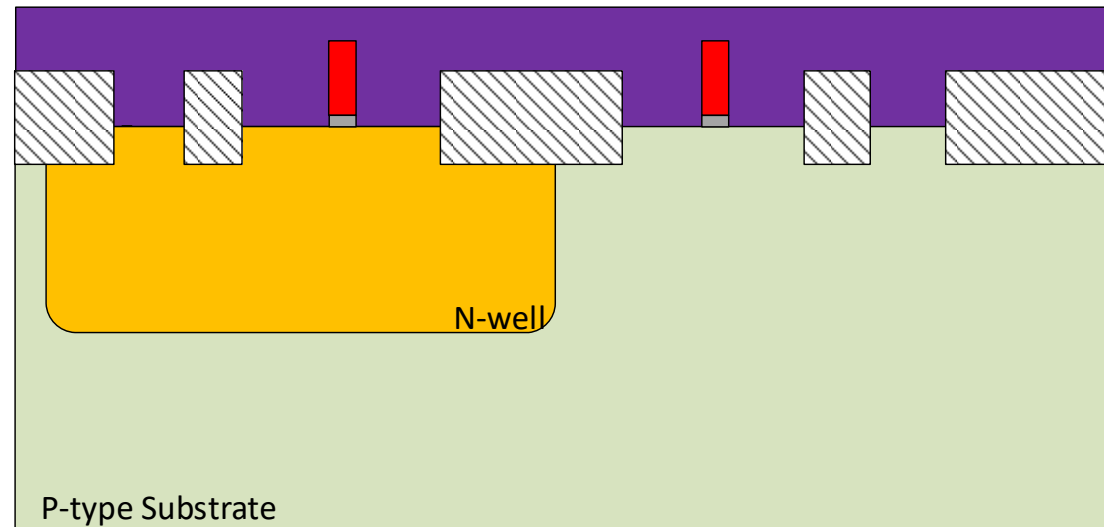
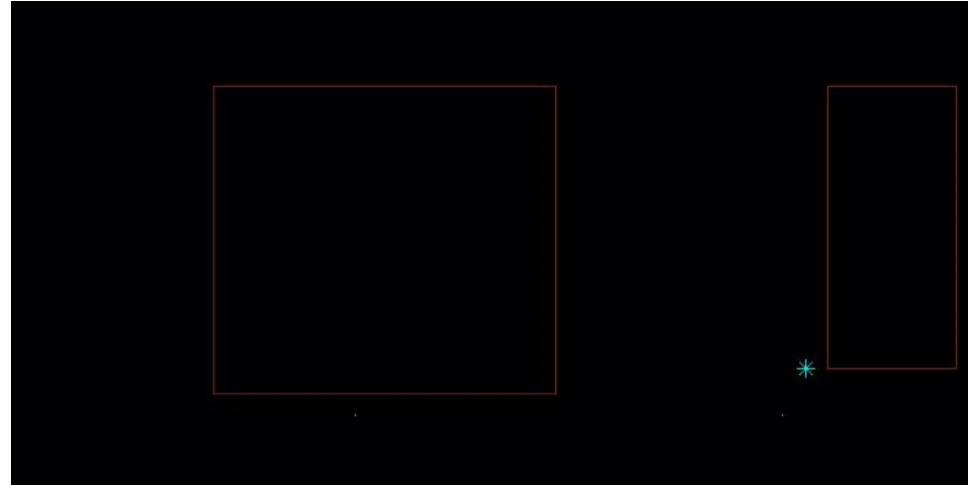


## 4.1: Build PMOS, Substrate Contact



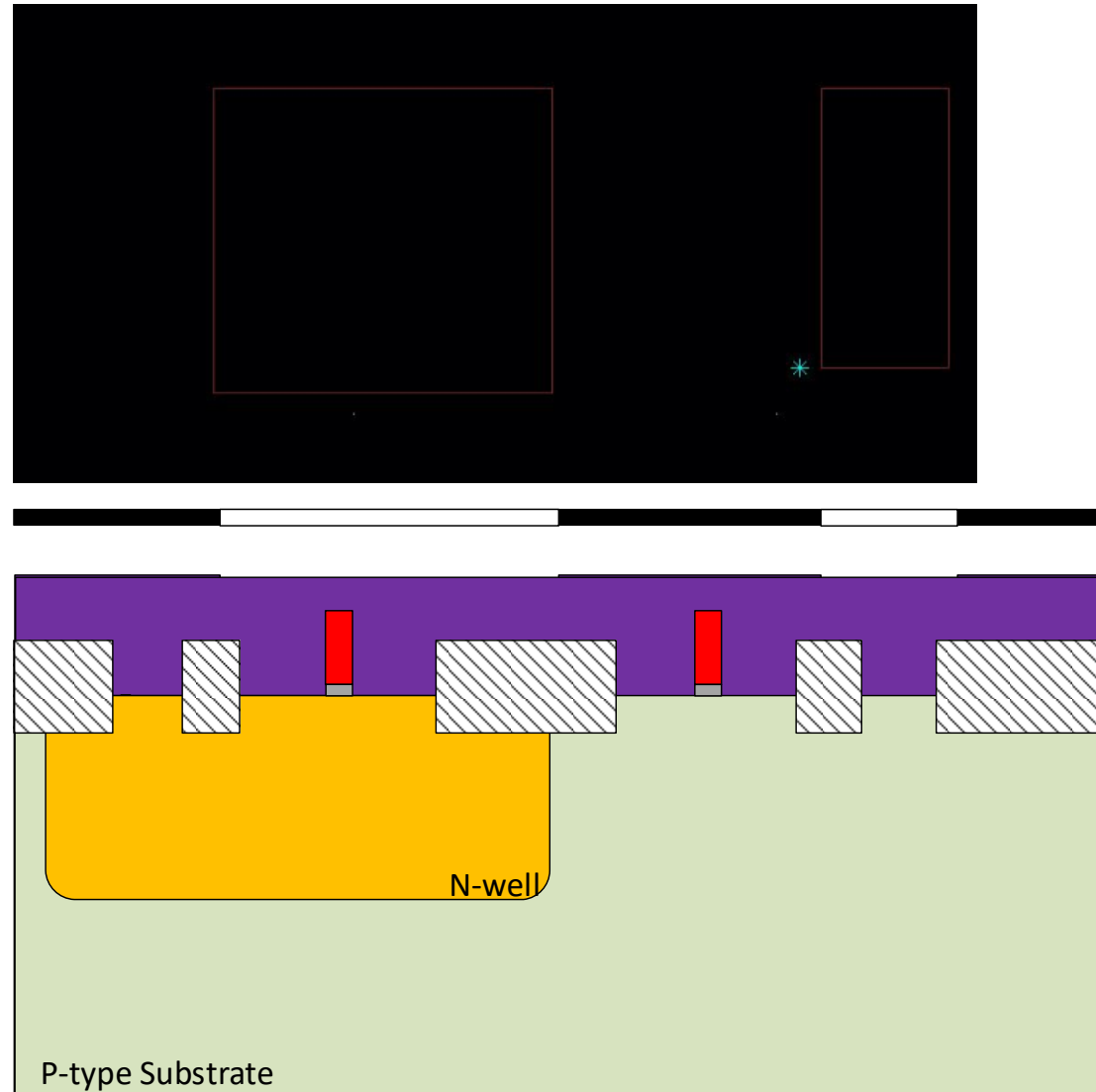
- Deposit photoresist

## 4.2: Build PMOS, Substrate Contact



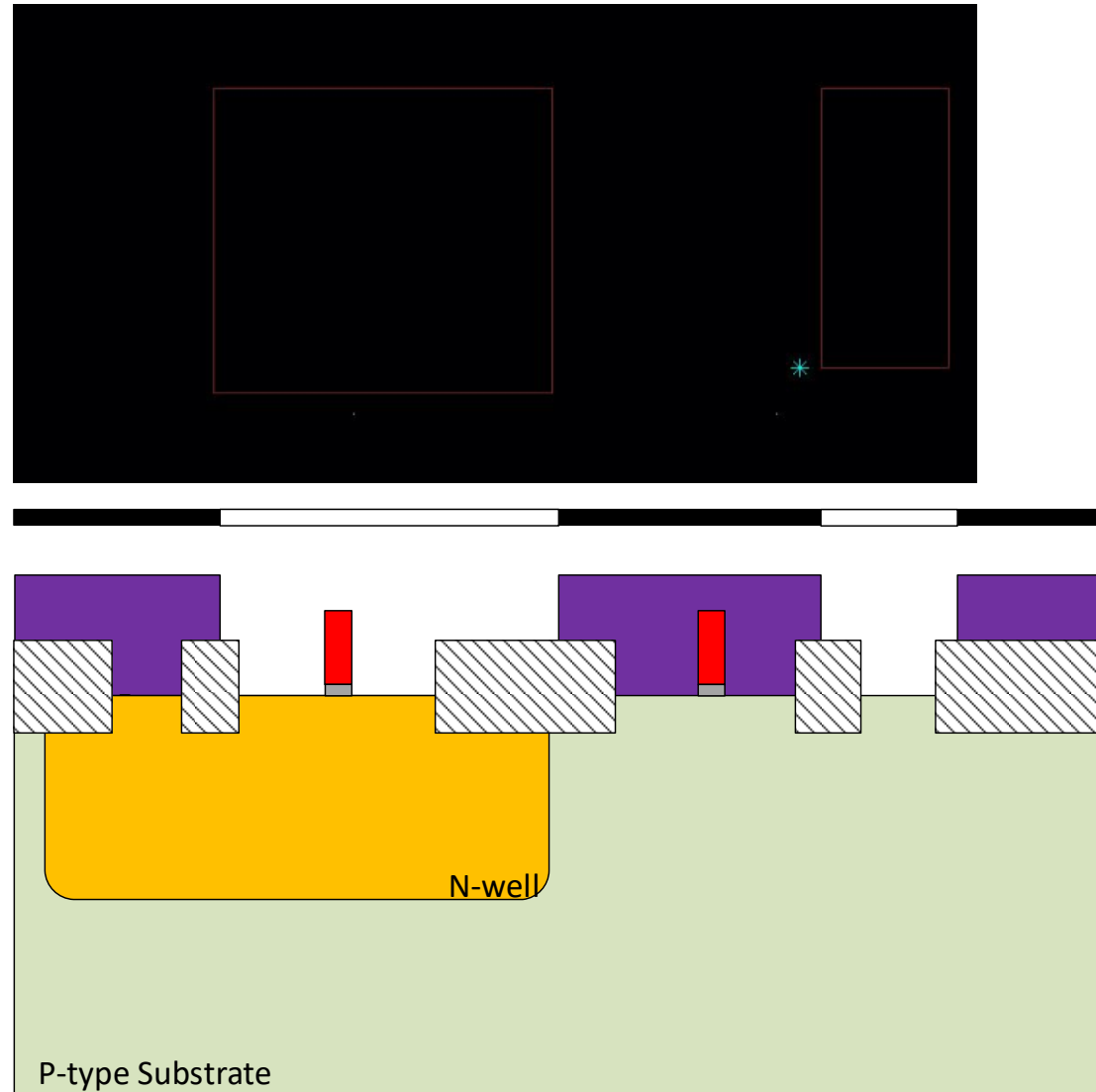
- Use PP mask to develop photoresist

## 4.2: Build PMOS, Substrate Contact



- Use PP mask to develop photoresist

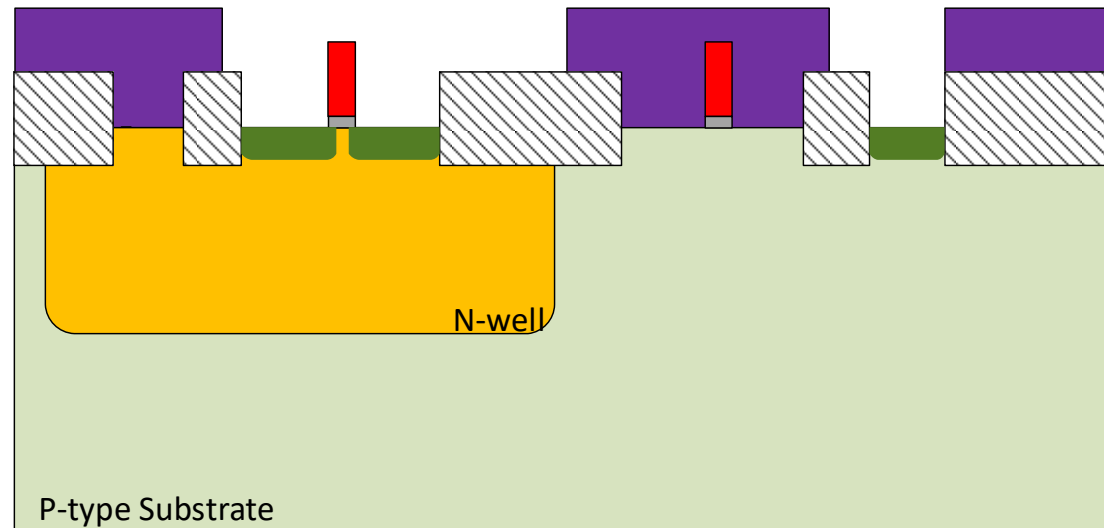
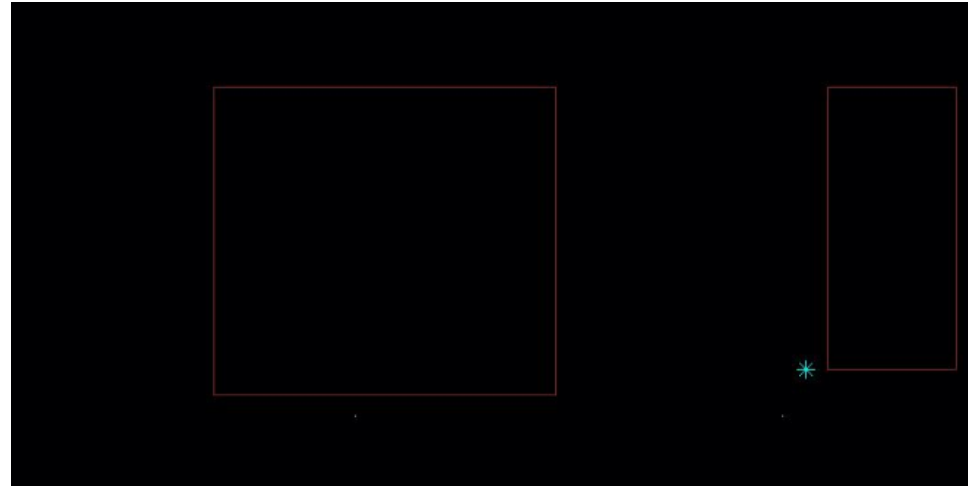
## 4.2: Build PMOS, Substrate Contact



- Use PP mask to develop photoresist

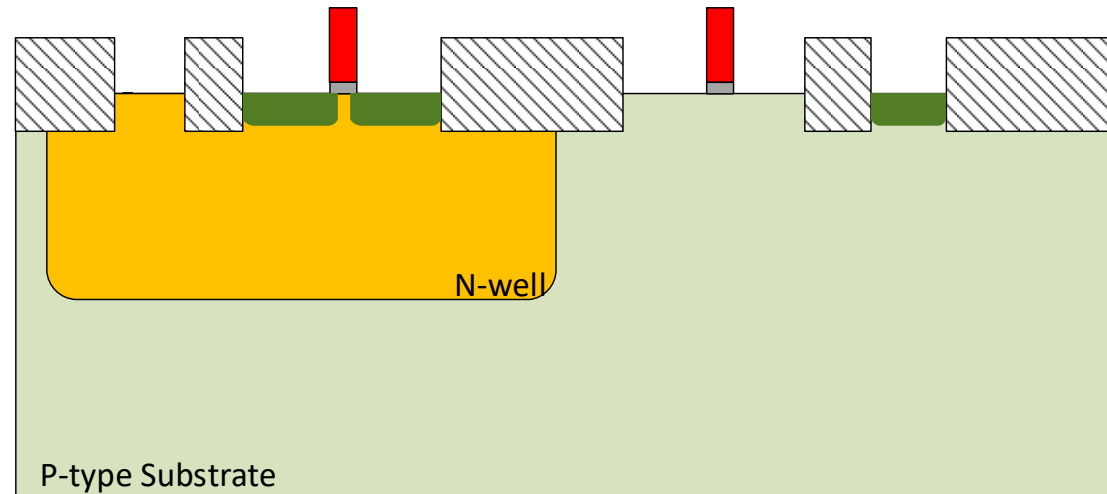
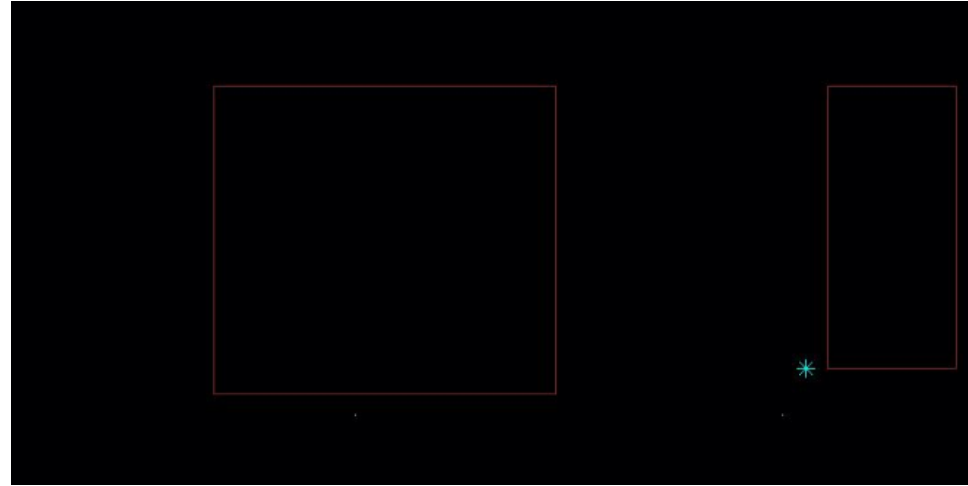
## 4.3: Build PMOS, Substrate Contact

Self-aligned gate :  
Implant n+/p+ after  
gate to automatically  
form gate exactly  
where it is needed



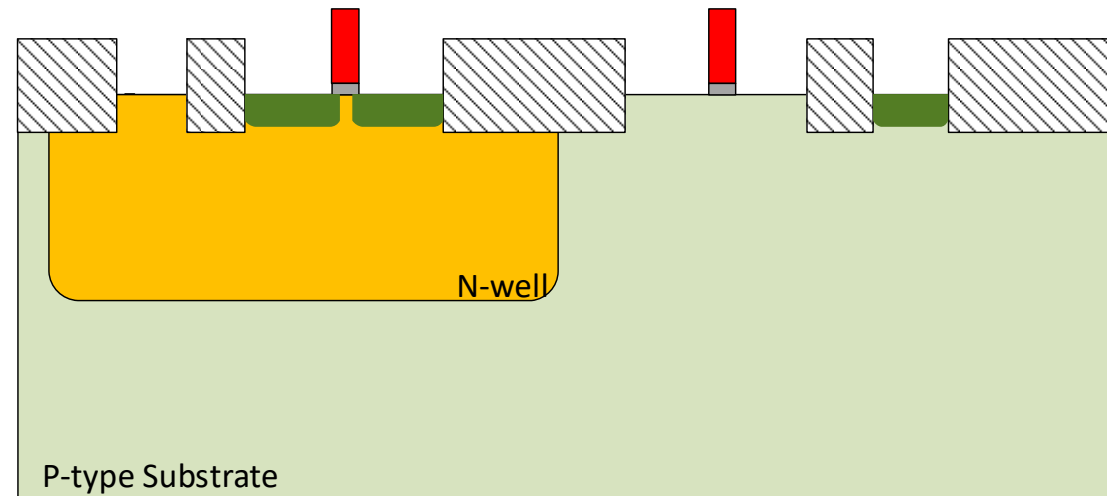
- Ion Implantation to create P+ regions for S/D and substrate contact

## 4.4: Build PMOS, Substrate Contact



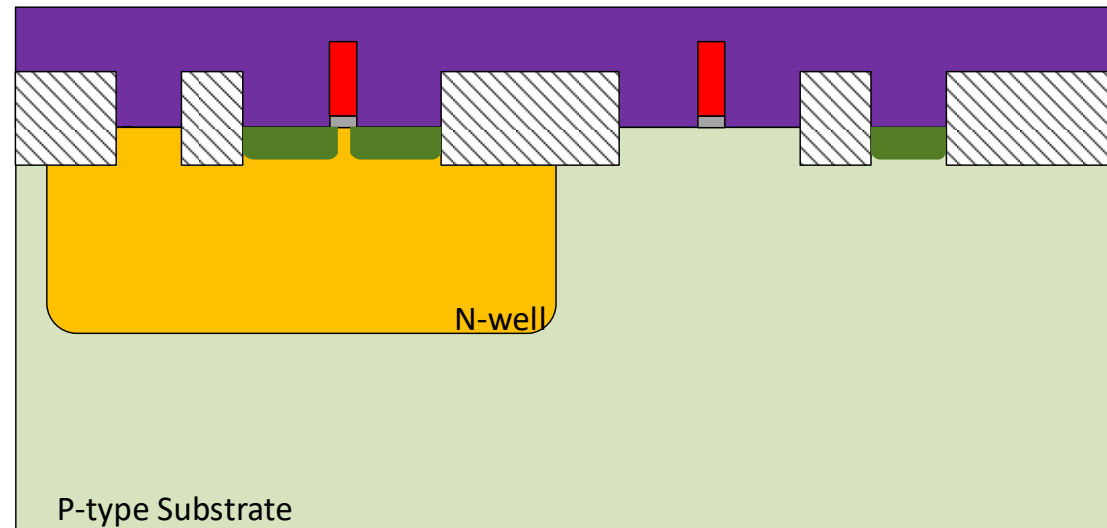
- Wash off photoresist

## 5:Build NMOS, Body Contact



- Next, we deposit N+ to form the Nmos S/D and body contacts

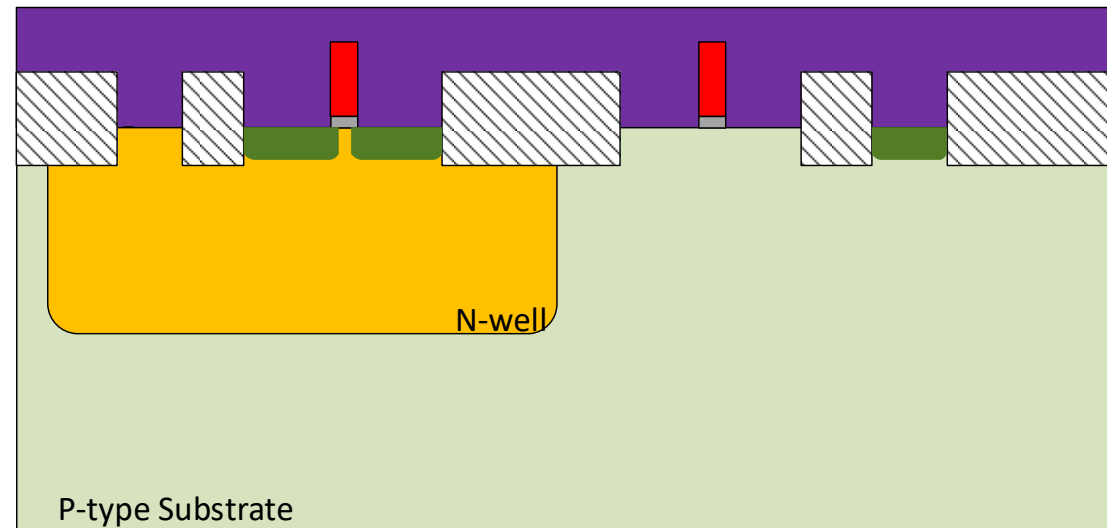
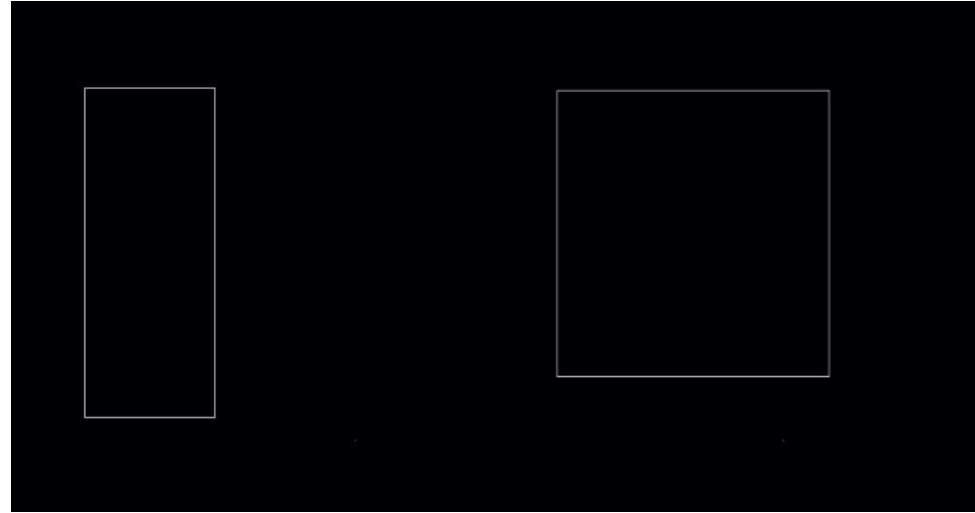
## 5.1: Build NMOS, Body Contact



- Photoresist

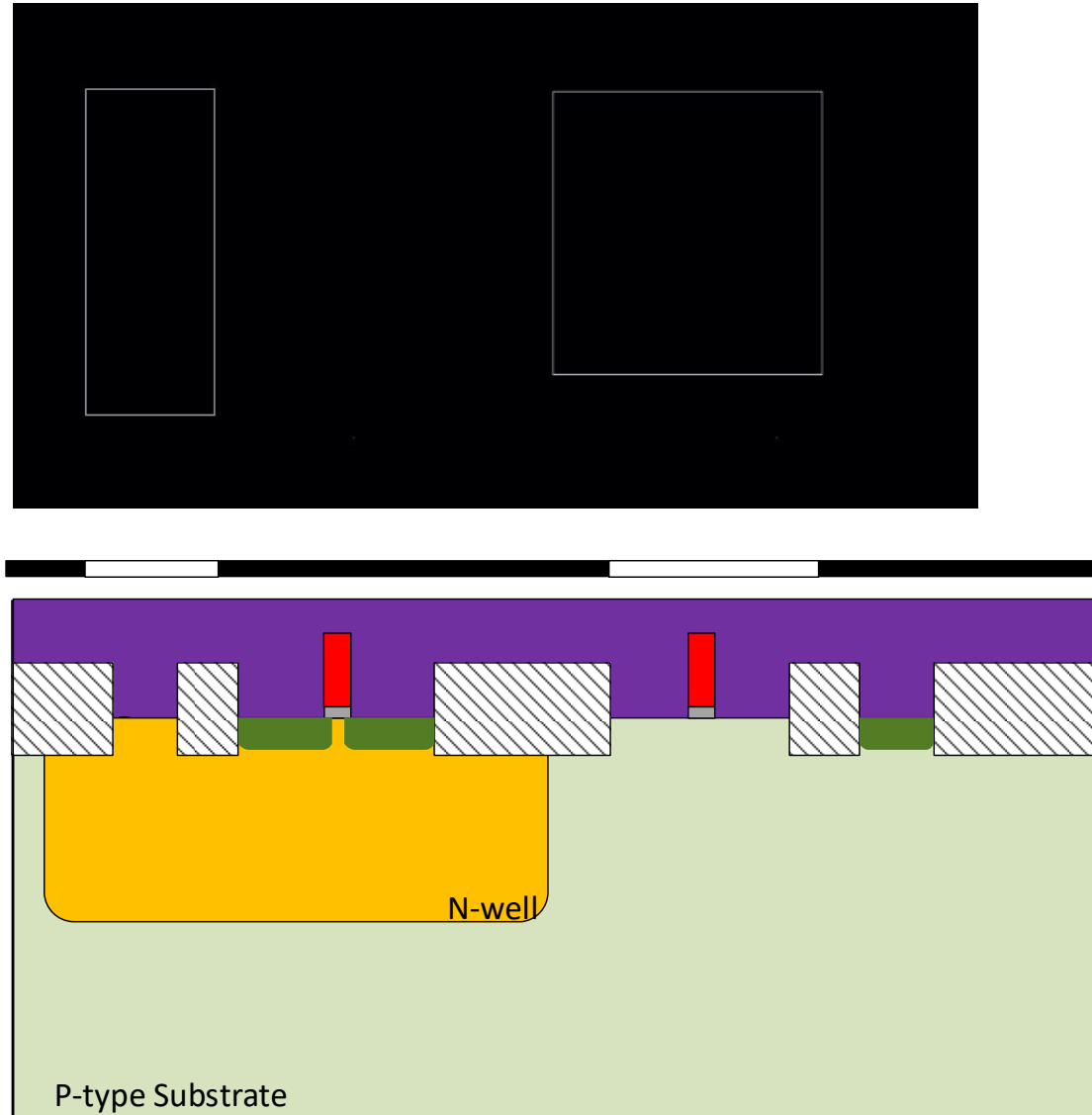


## 5.2: Build NMOS, Body Contact



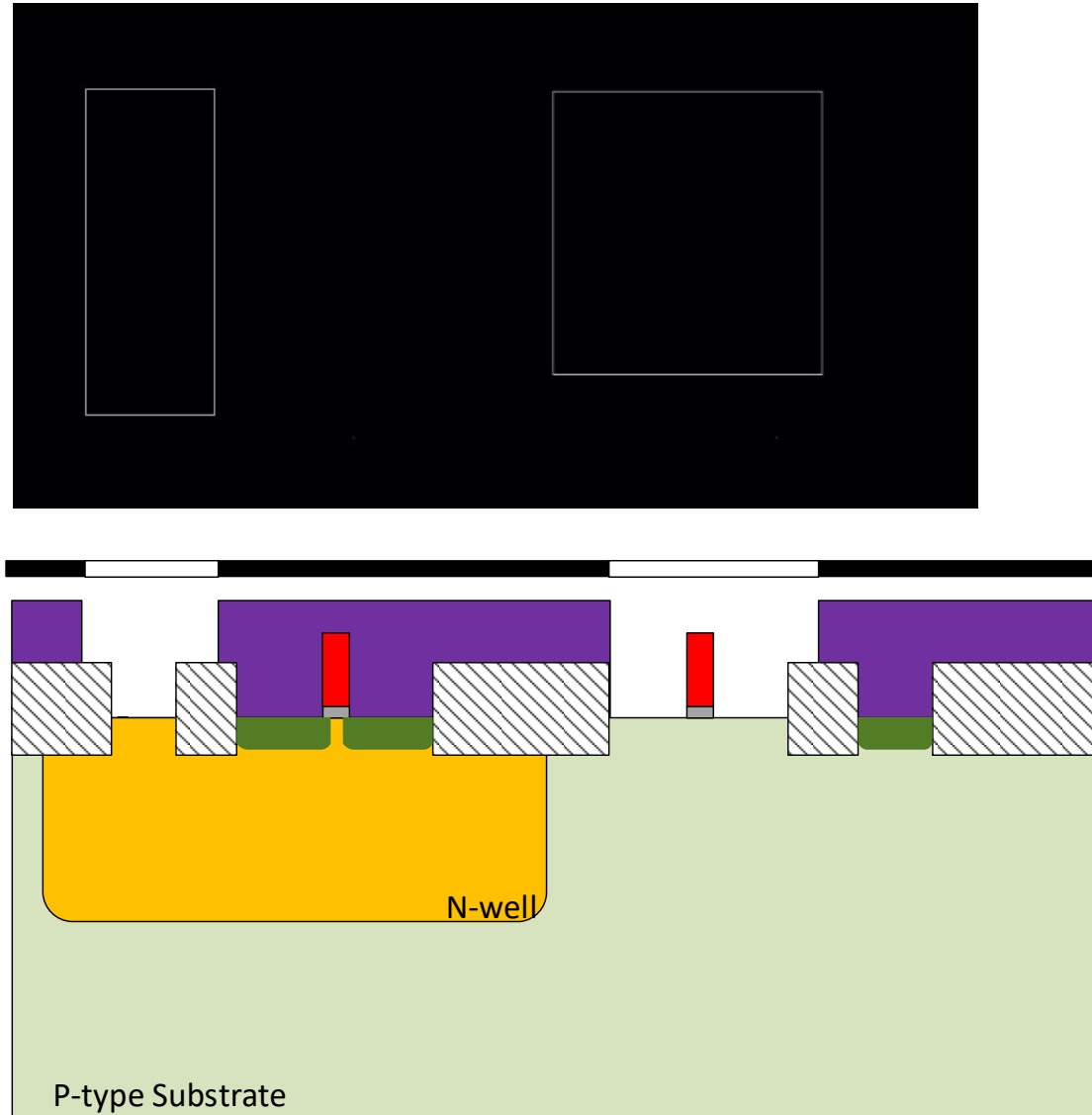
- Use NP mask to develop photoresist

## 5.2: Build NMOS, Body Contact



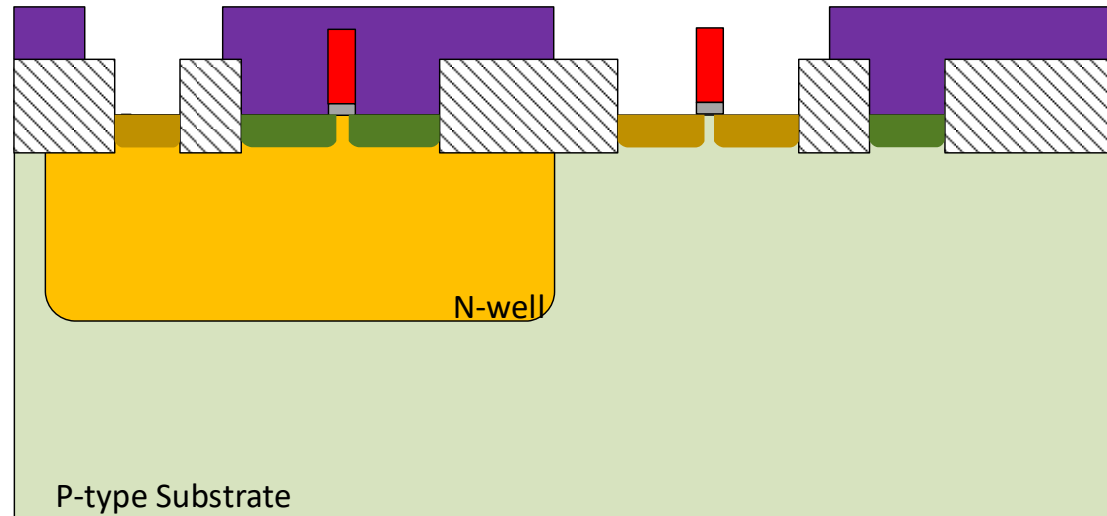
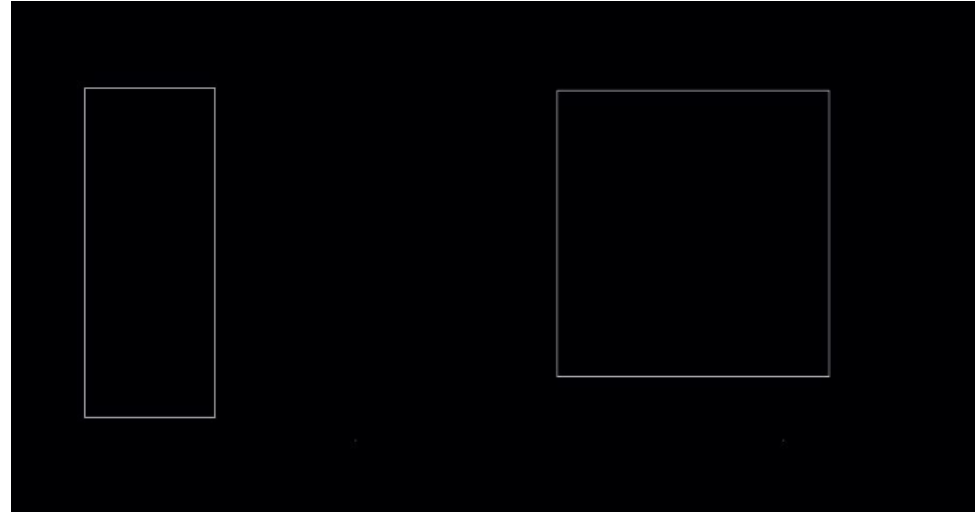
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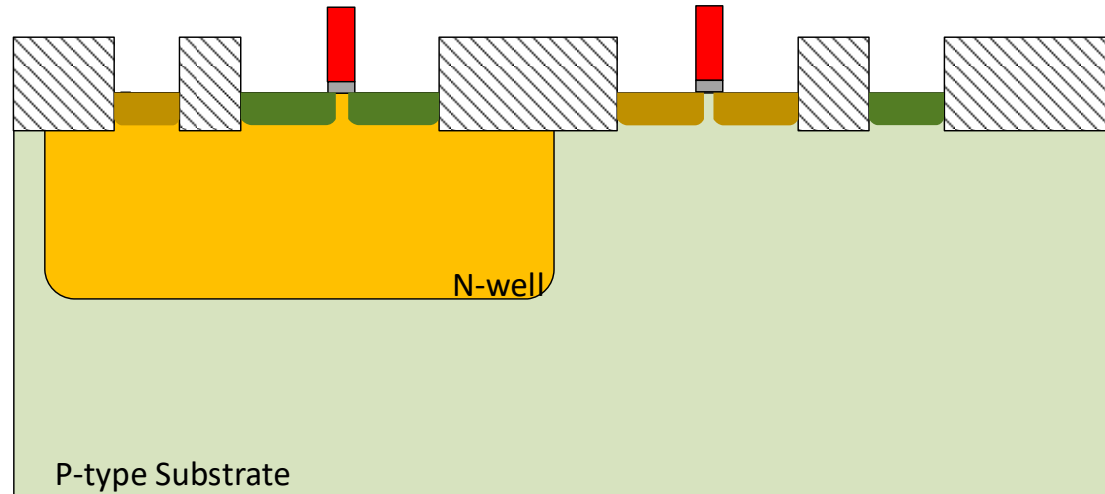
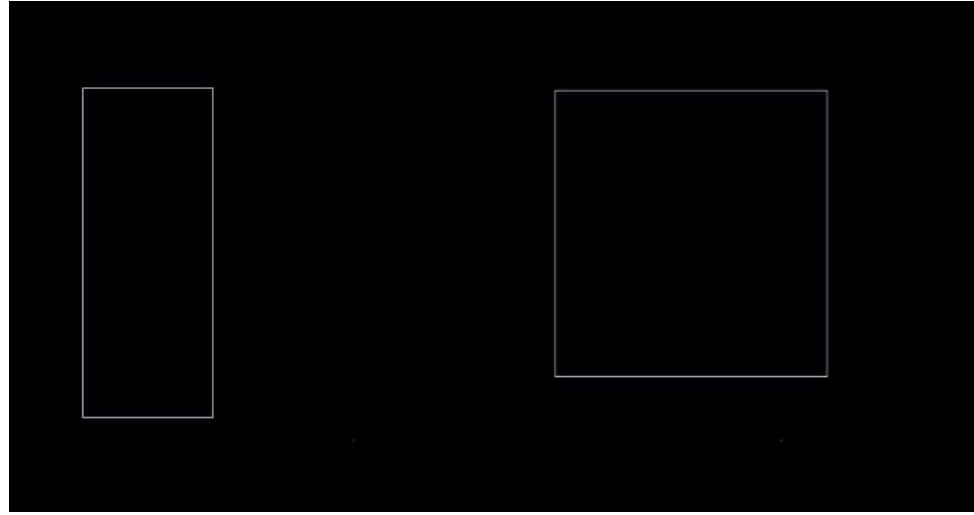
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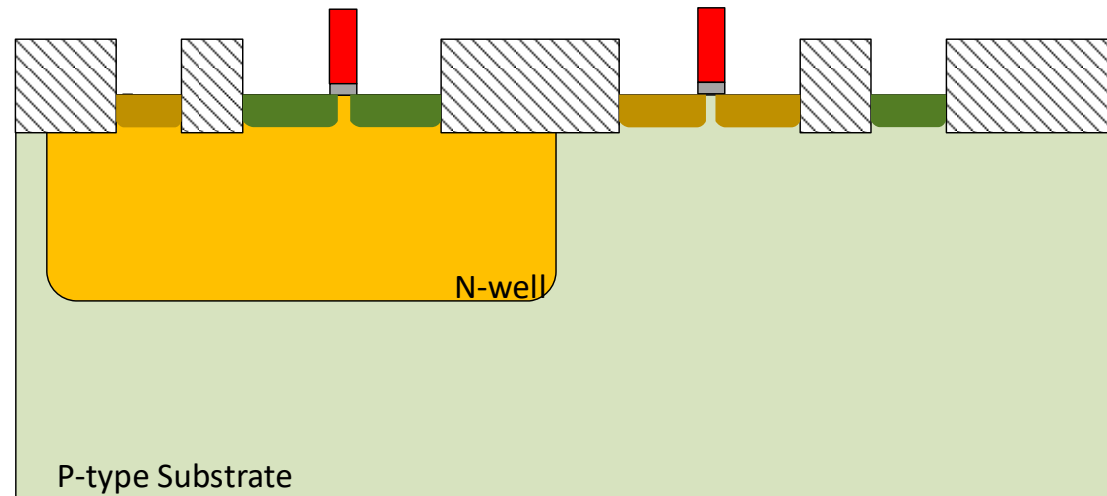
- Etch photoresist

## 5.4: Build NMOS, Body Contact



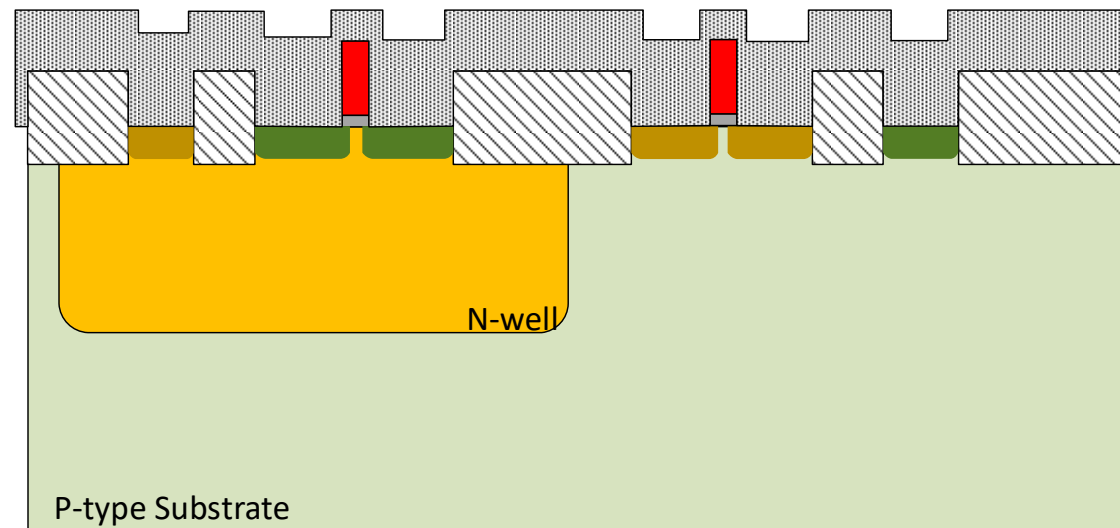
- Deposit N+, wash photoresist

## 6: Contacts to metal



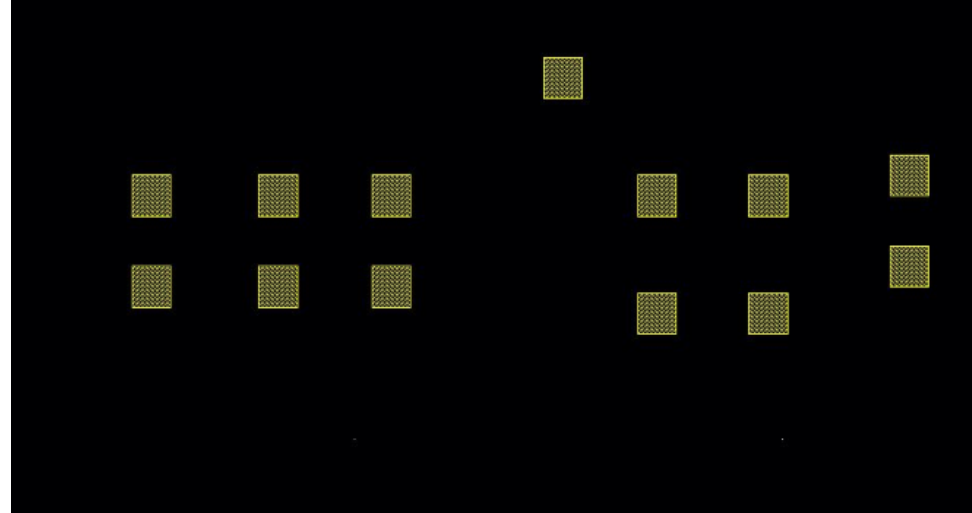
- Deposit N+, wash photoresist

## 6.1: Contacts to metal

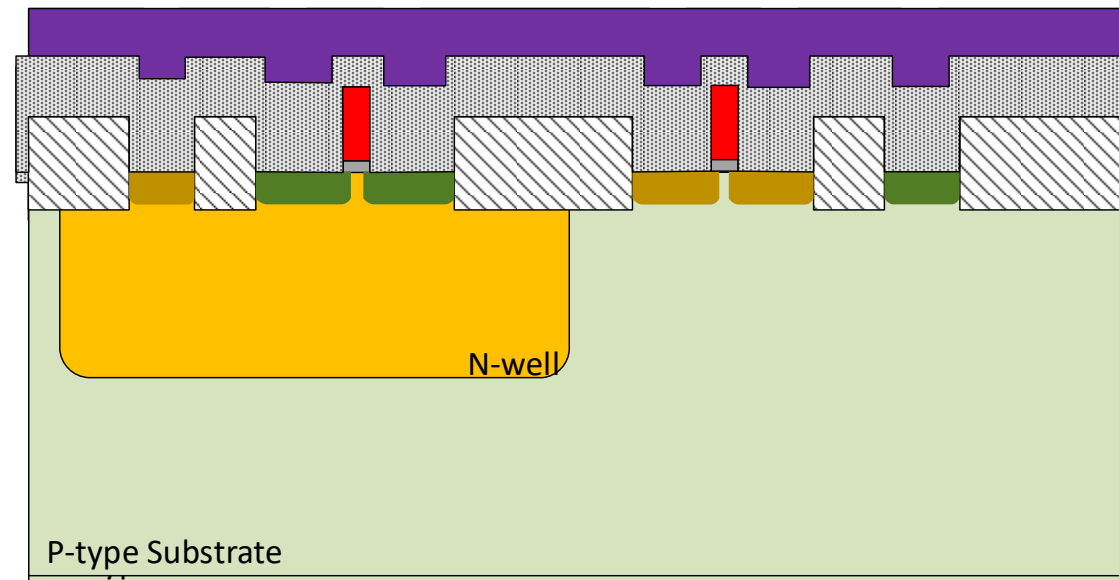


- Deposit oxide layer (metal-oxide-metal-oxide.... from here on)

## 6.2: Contacts to metal

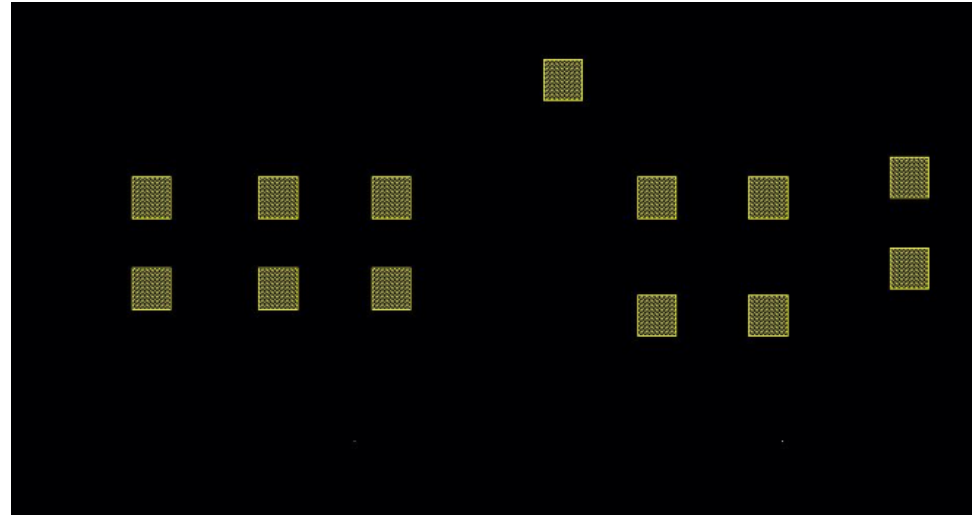


What happened to  
PO contact?

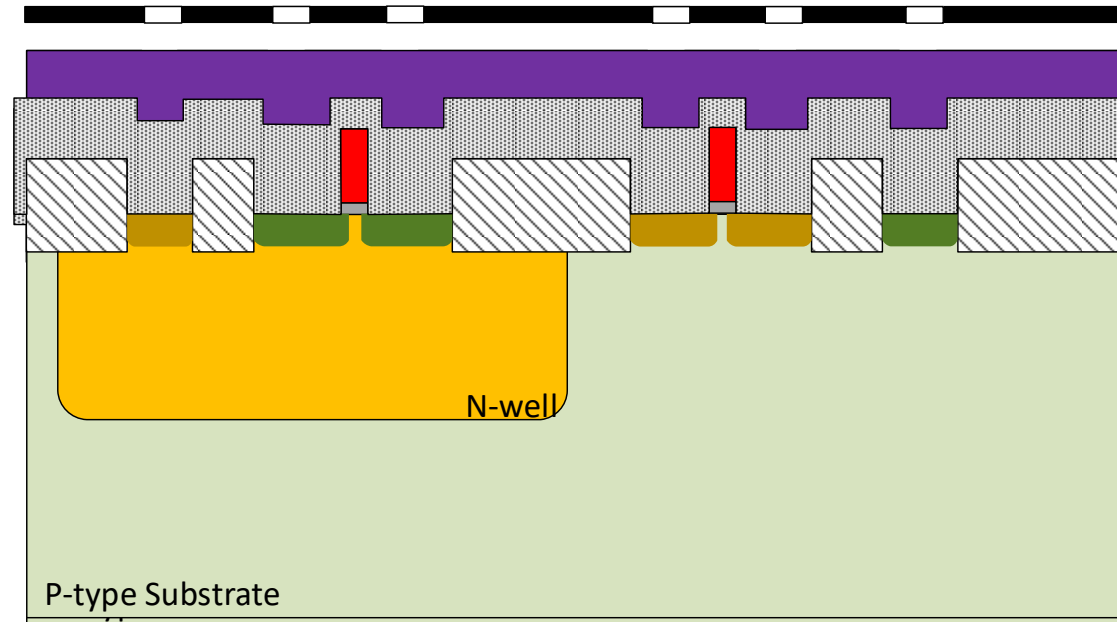




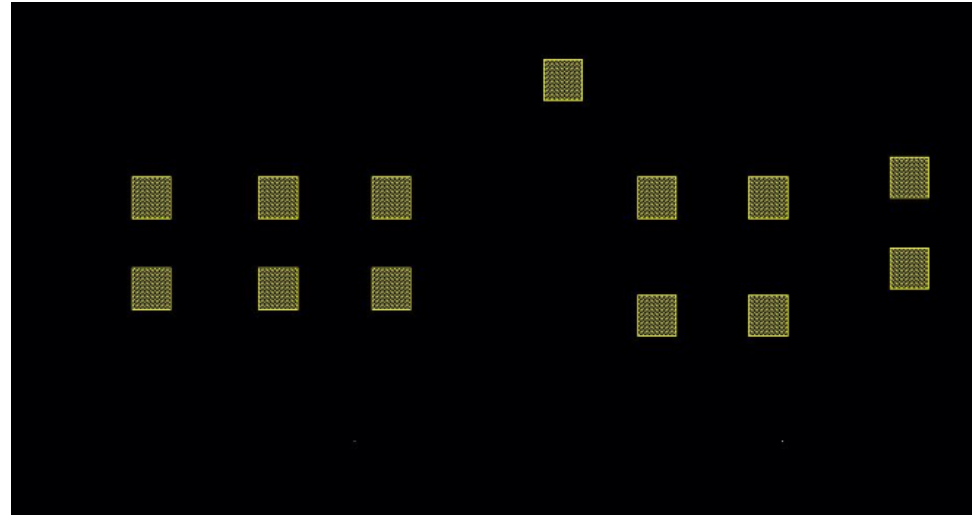
## 6.2: Contacts to metal



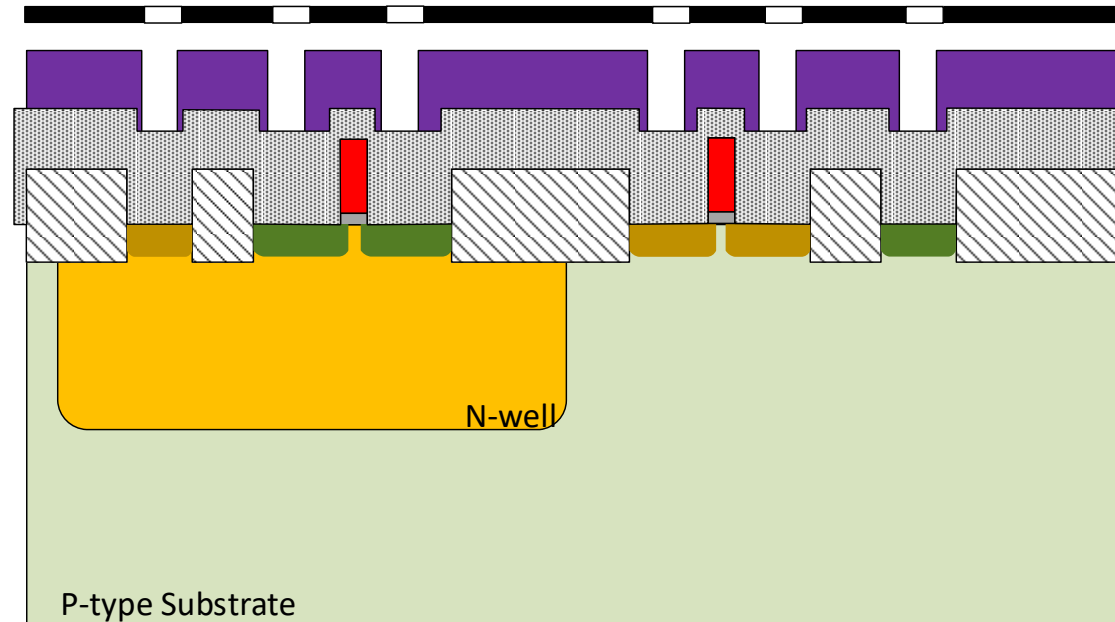
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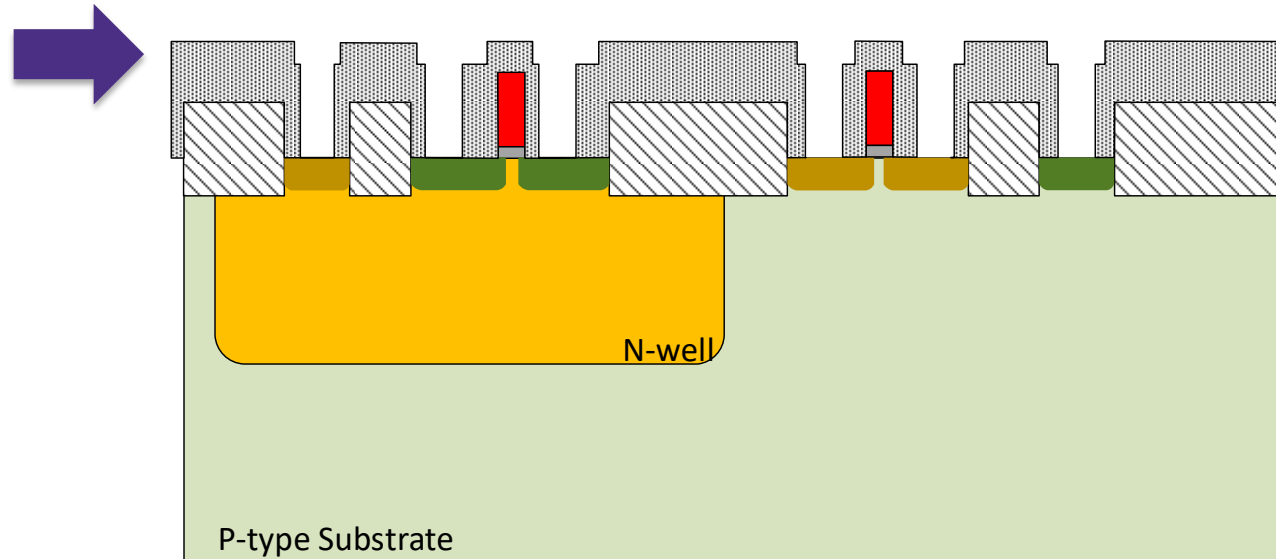
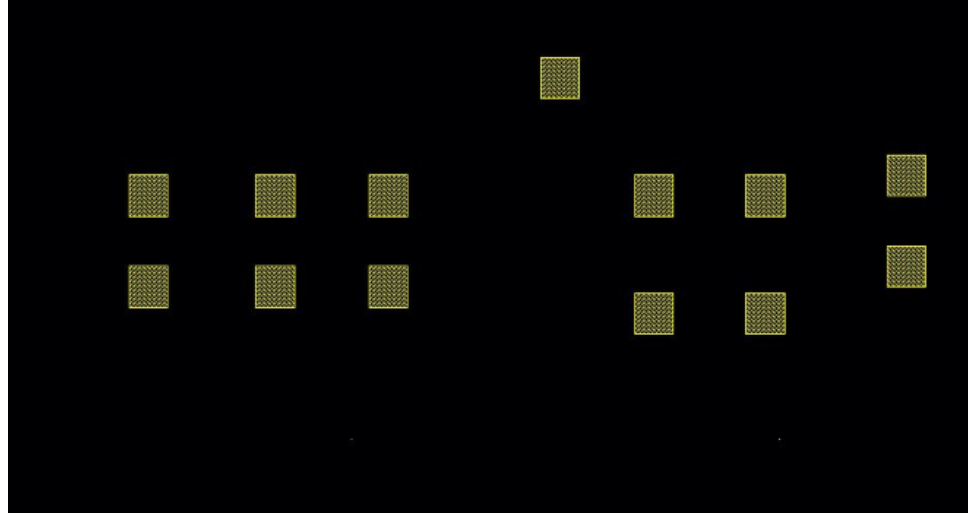
## 6.2: Contacts to metal



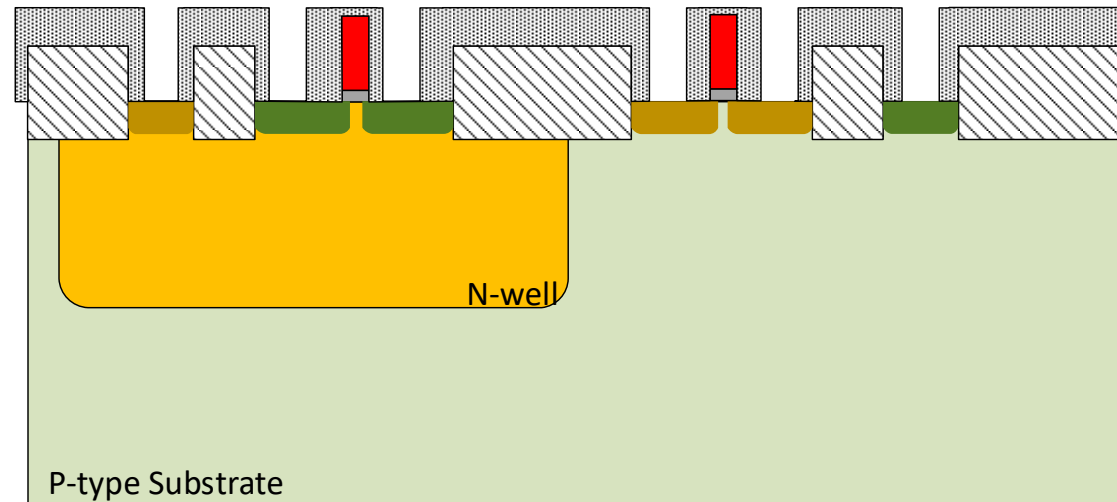
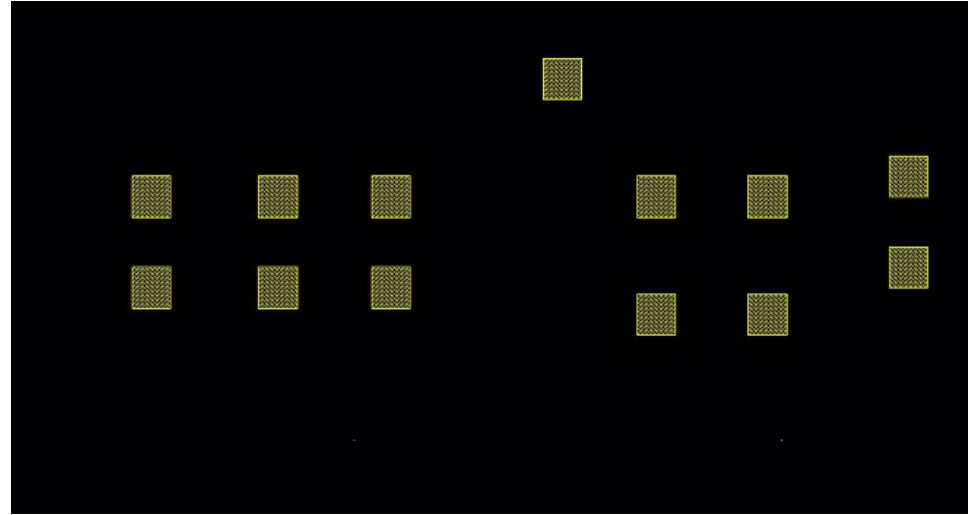
What happened to  
PO contact?



## 6.3: Contacts to metal

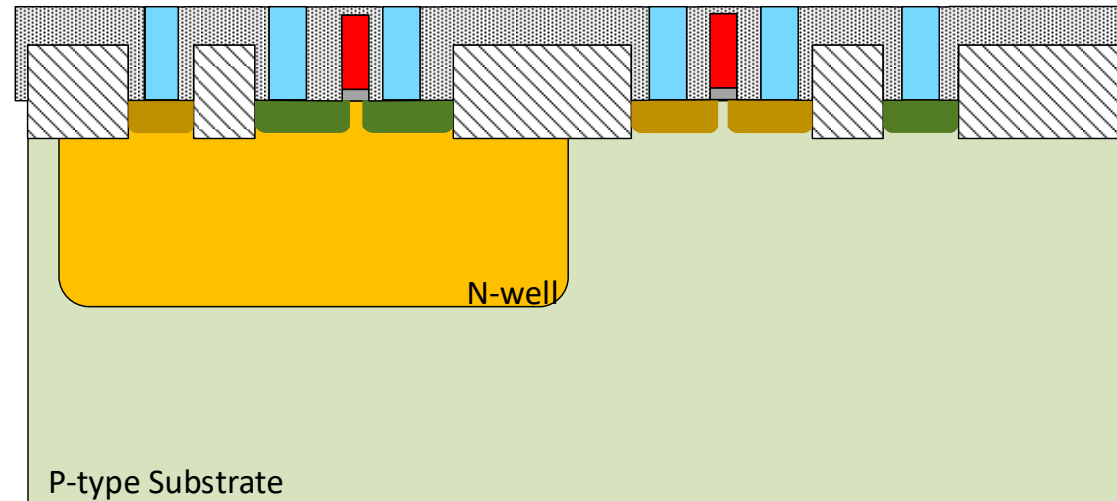
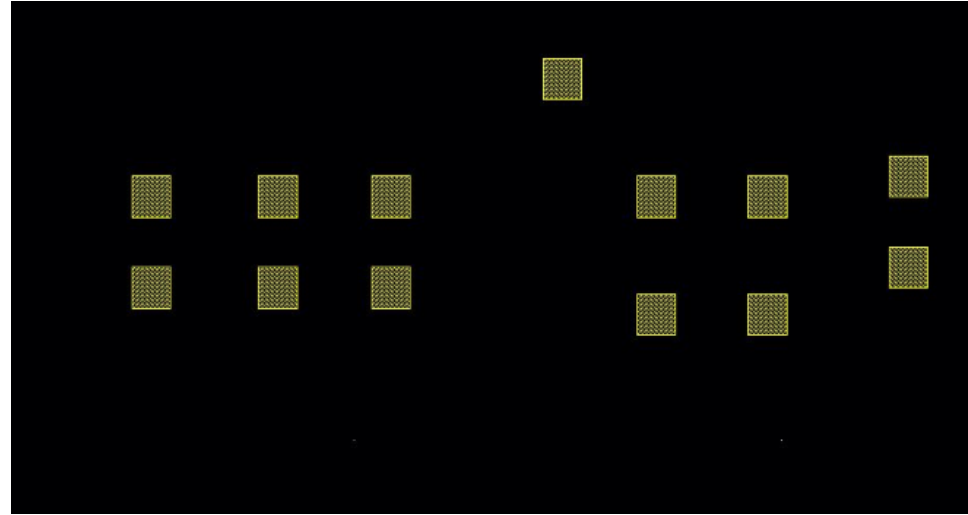


## 6.4: Contacts to metal

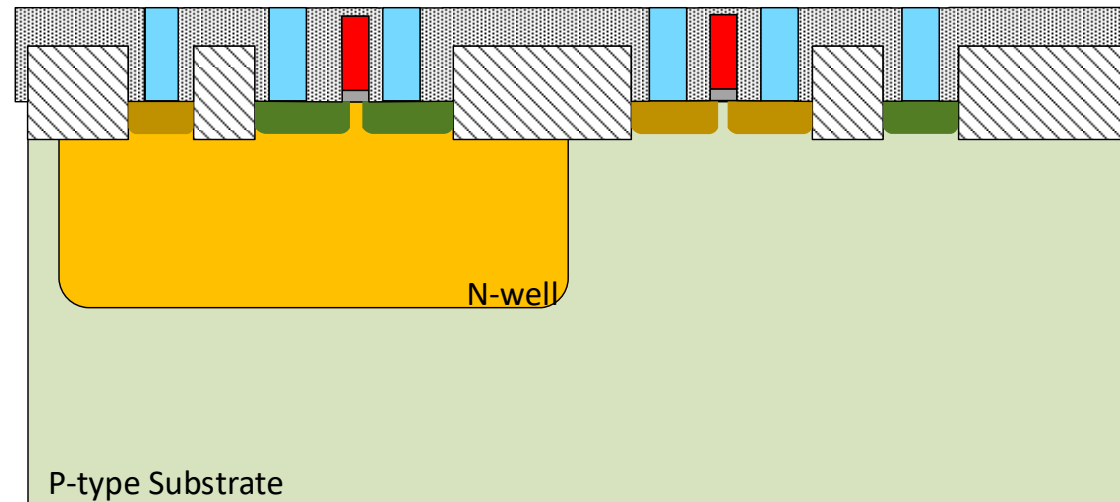


- Polish to even out topography

## 6.5: Contacts to metal

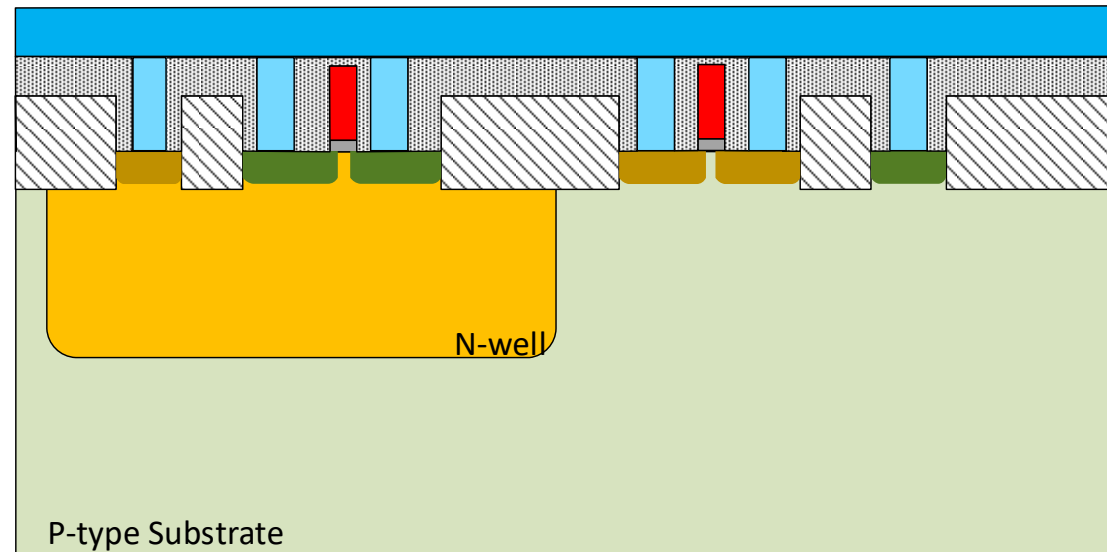


- Deposit contact material



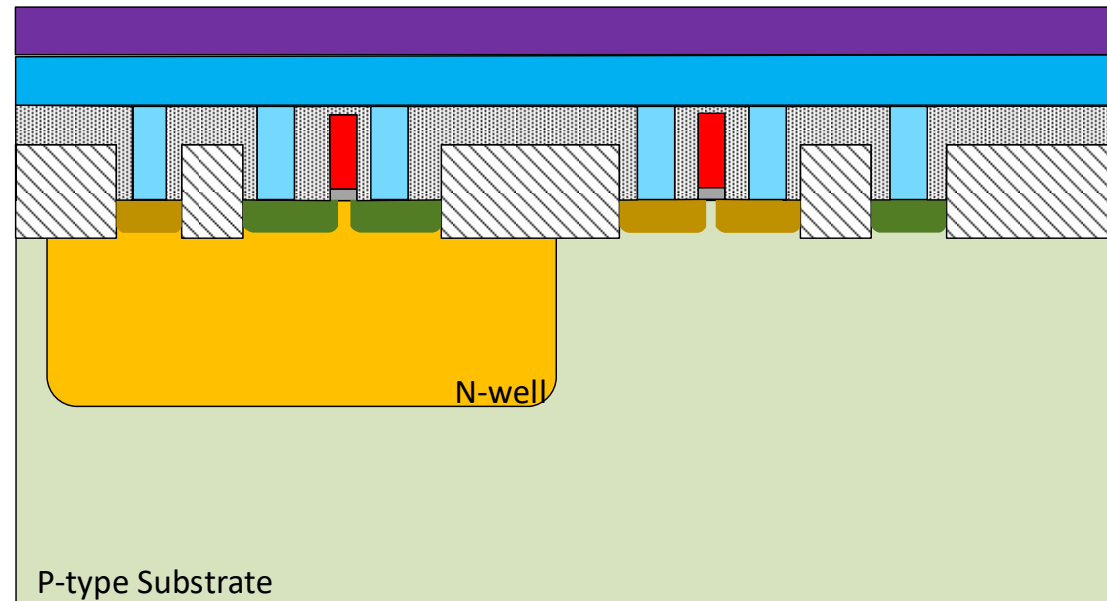
- Fabricate the Metal to connect the transistors (only M1 shown)

## 7.1: Metal



- Fabricate the Metal to connect the transistors (only M1 shown)

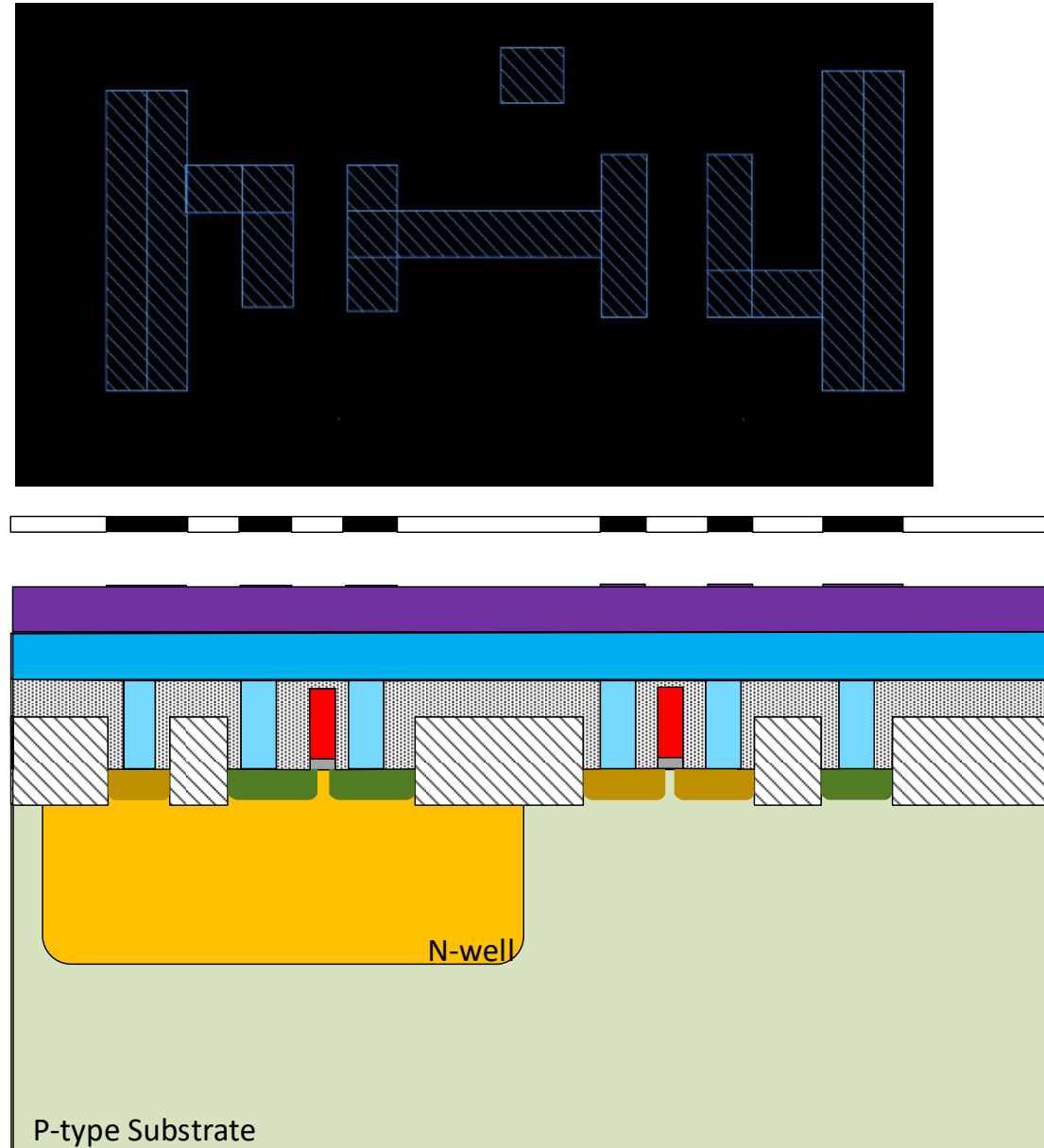
## 7.1: Metal



- Fabricate the Metal to connect the transistors (only M1 shown)

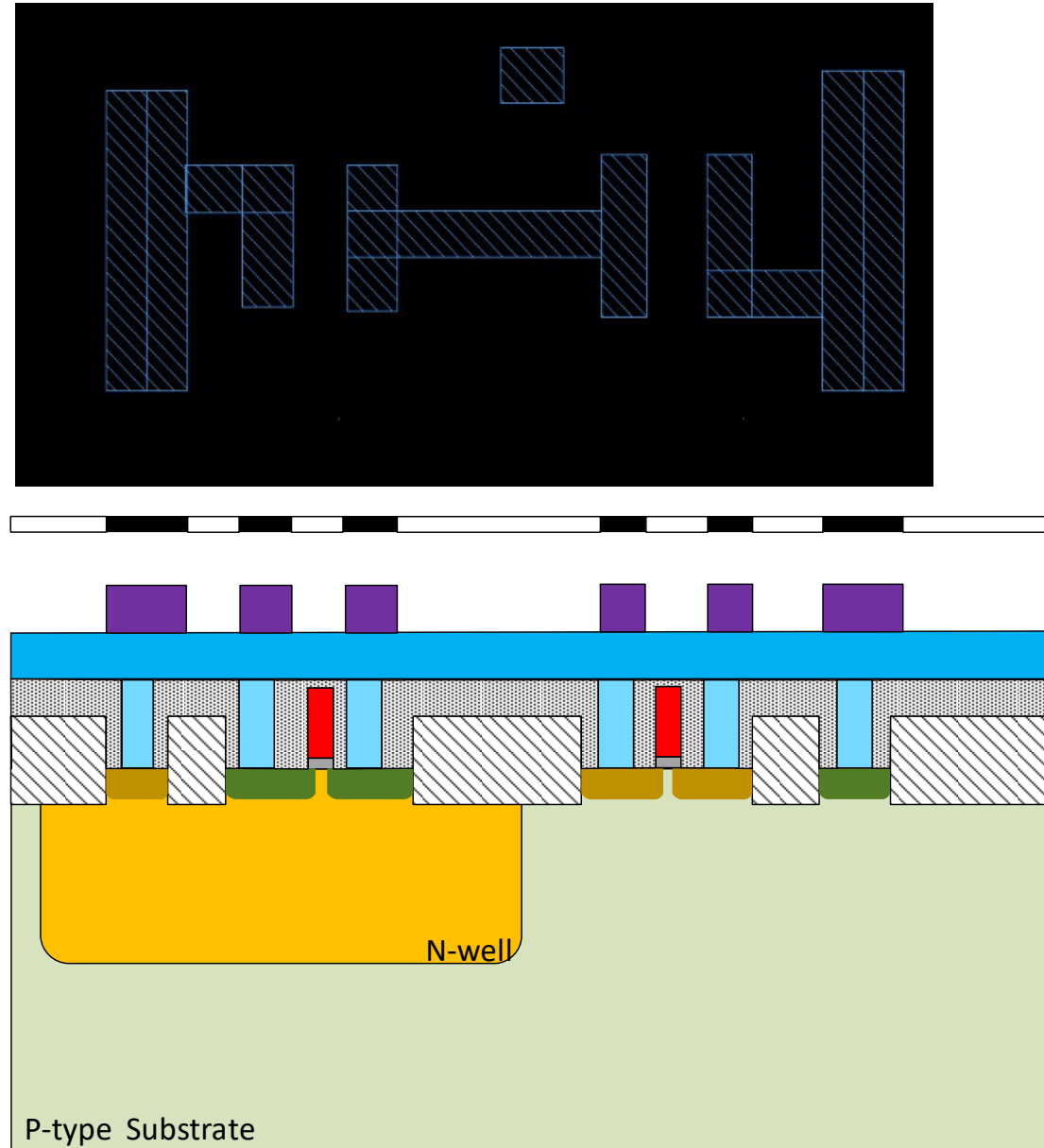


## 7.1: Metal



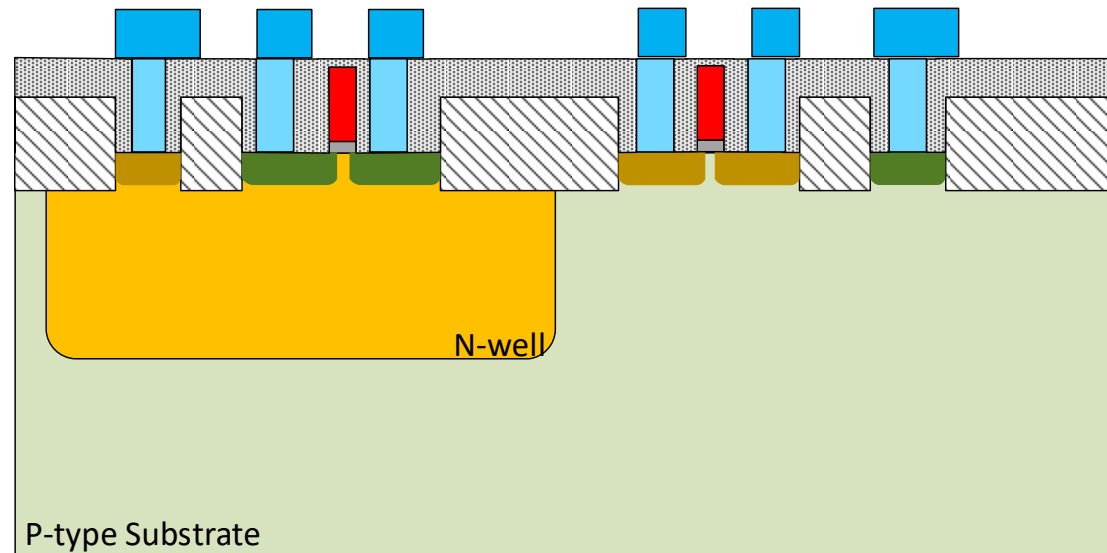
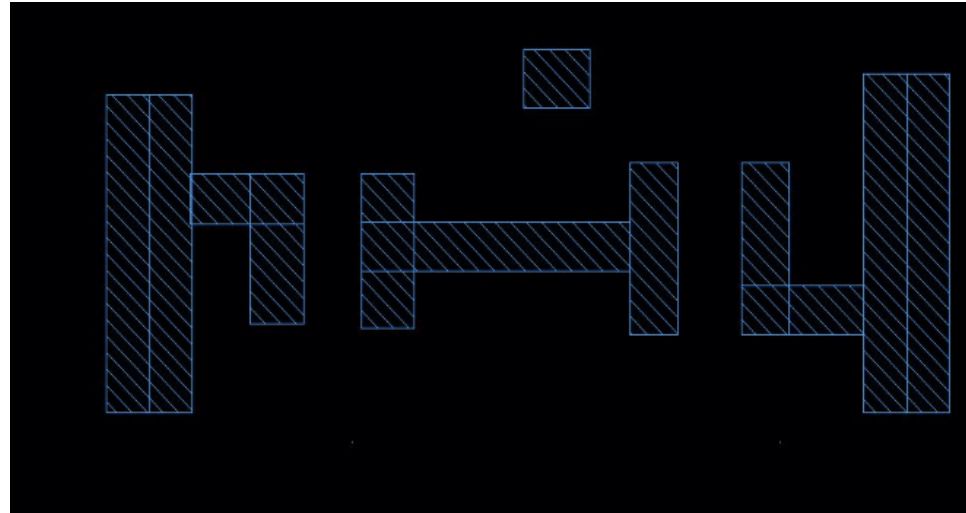
- Fabricate the Metal to connect the transistors (only M1 shown)

## 7.1: Metal



- Fabricate the Metal to connect the transistors (only M1 shown)

## 7.1: Metal



- Fabricate the Metal to connect the transistors (only M1 shown)

# Key Fabrication Steps

- Depositing material
  - Epitaxial growth (Si)
  - CVD (Chemical-Vapor Deposition), used for via/metals
  - Diffusion/Ion-implantation (For dopants to create N-Well, N+, P+)
  - Reaction
    - $\text{SiO}_2$  : Used for form field-oxide, gate-oxide, barrier for ion-implantation
    - $\text{Si}_3\text{N}_4$  : Inert, used as a means to prevent oxidation during formation of field-oxide
- Patterning (Lithography)
  - Apply photoresist
  - Use mask to selectively soften photoresist (for + photoresist)
  - Remove softened photoresist (photoresist, expose->soluble to developer, wash it off)
  - Perform selective deposition/etch step
  - Etch away remainder of the photoresist using a *piranha* etch
- Maintain even topography – Chemical Mechanical Polish (CMP)
- Etching ( $\text{SiO}_2$ ,  $\text{Si}_3\text{N}_4$ , Metal, Photoresist and many more...)

# Additional Notes

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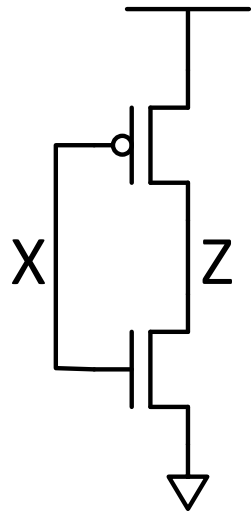
- LOCOS no longer used in scaled processes
  - “Birds-beak” requires too much separation, area hit
  - Use Shallow Trench Isolation instead
- “Poly” is now done using Metal Gate
  - Avoid effective oxide thickness increase seen with poly
  - Lower gate resistance
- Oxides
  - Gate oxide is a High-K material\*
  - Inter-layer dielectric (ILD), between metals use low-K dielectrics
- Latest CMOS technologies use a tri-gate (finfet) structure. No planar MOSFETs
  - Better short channel effects
  - Restrictive in device widths
- Modern processes use many more masks and stages than shown here

# Design Rule Checks (DRCs)

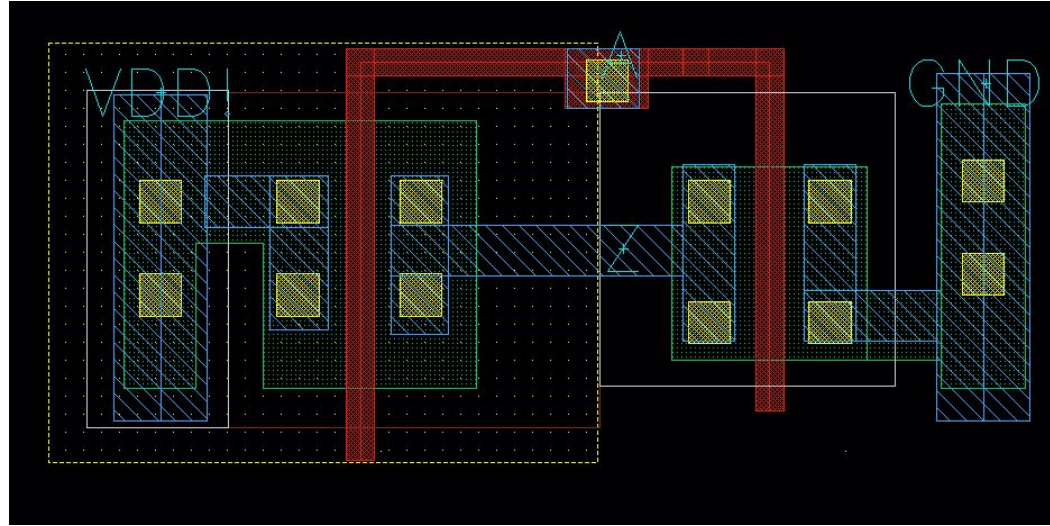
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- Modern microprocessors have >4billion transistors
- Every one of them, and their connecting wires needs to work
- Design Rule Checks
  - Enforce constraints that must be met by mask geometries
    - Min-spacing (Avoid shorts, leak-paths)
    - Min-width (Avoid pinch-off)
    - Overlap (Ensure sufficient intersection, enclosure)
    - Density checks (Global and Local)
  - Violation causes shorts, opens, parametric yield loss

# Layout vs. Schematics (LVS)

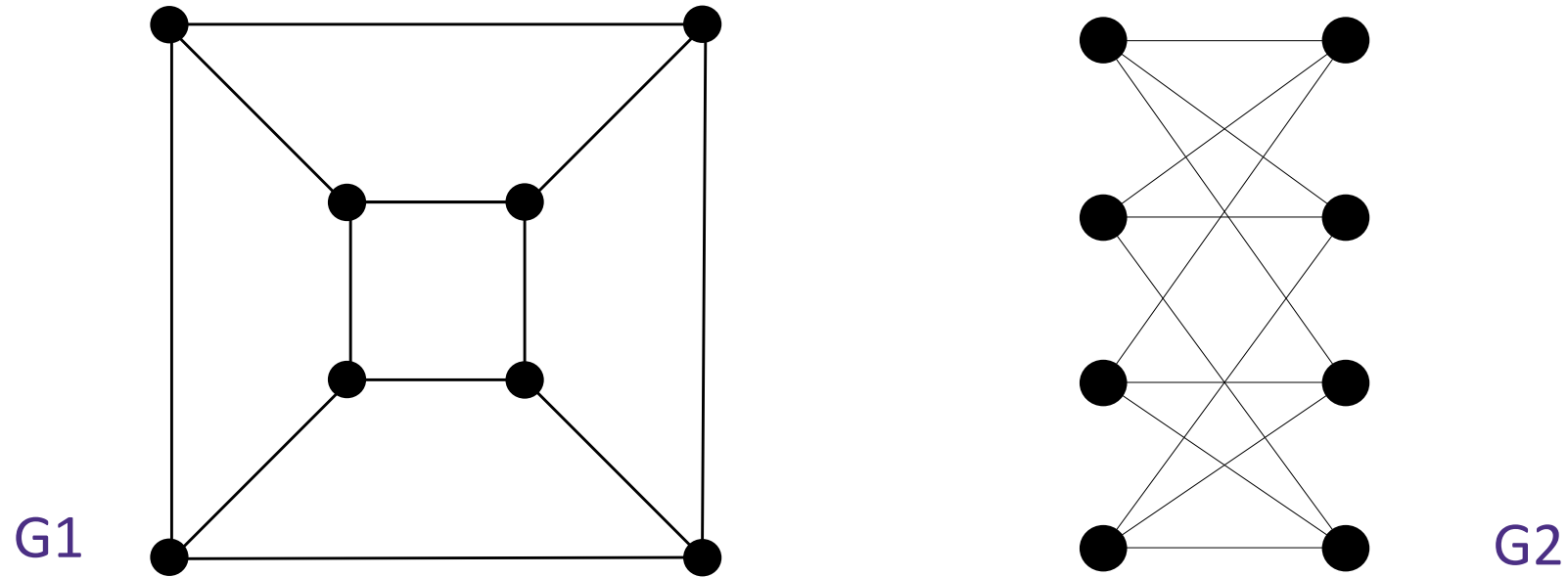


V.S.



- Complex design environments → Design is entered and evaluated at a higher level of abstraction
  - C/C++
  - HDL
  - At least schematics
- Layout then created. Mask must match required functionality
- Problem of checking whether Layout = Schematic essentially a check for graph isomorphism

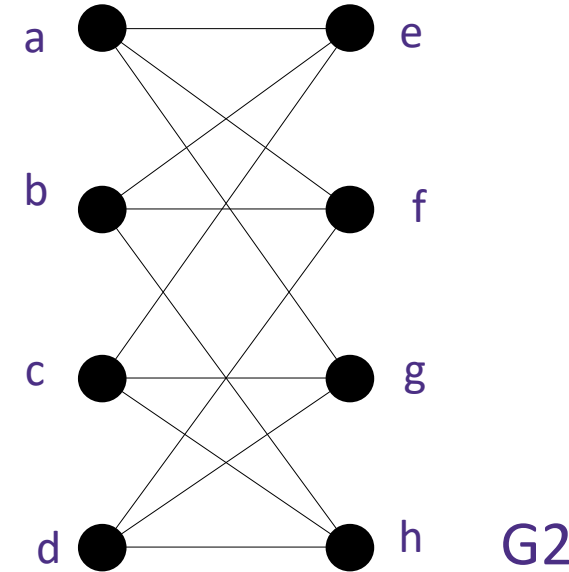
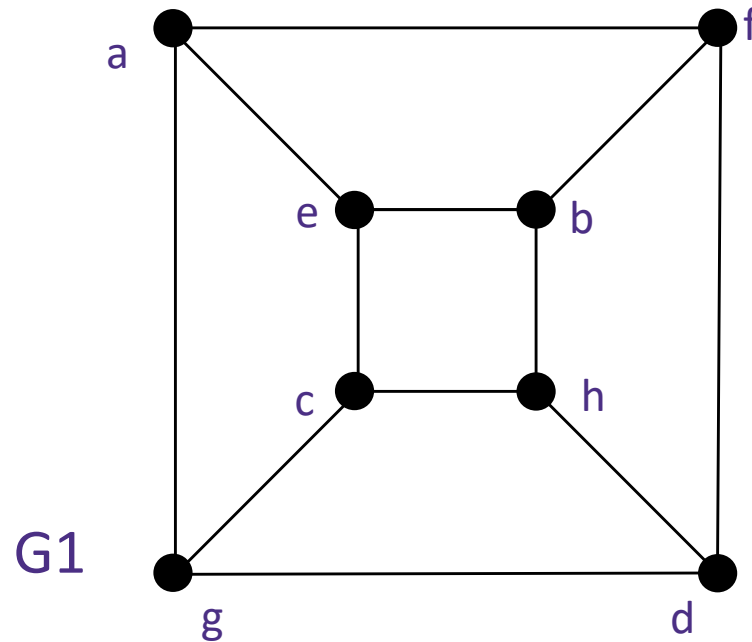
# Quick de-tour: Graph Isomorphism



- “A one-on-one and onto” mapping between nodes,  $f$ 
  - $f: V(G_1) \rightarrow V(G_2)$
  - $G_1$  and  $G_2$  are isomorphic:  $a, b$  adjacent in  $G_1 \Leftrightarrow f(a), f(b)$  adjacent in  $G_2$
- LVS seeks to determine if there is an isomorphism between the schematic graph and the layout graph.
  - Include edge properties (fetWidth etc.) in addition to just connections



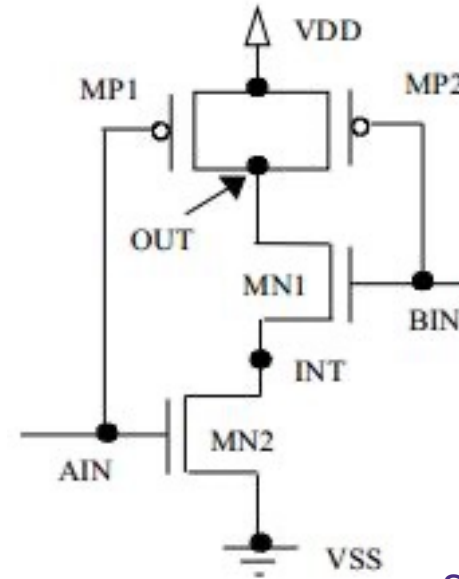
# Quick de-tour: Graph Isomorphism



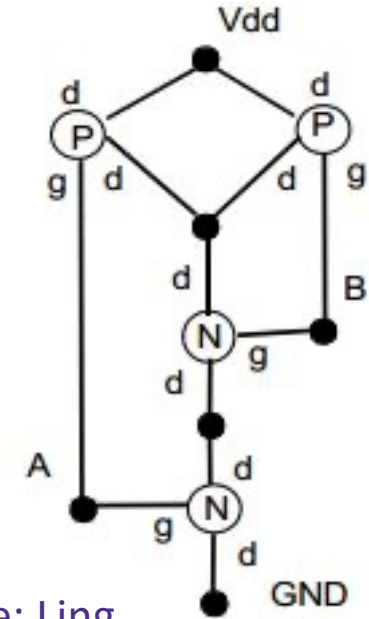
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# LVS operation

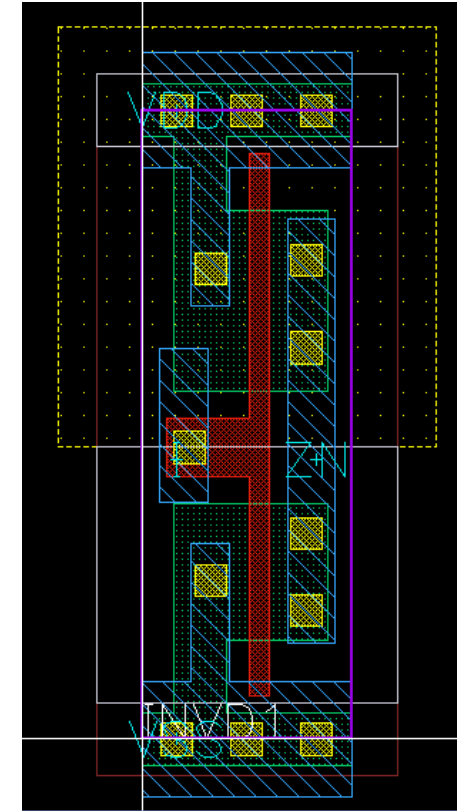
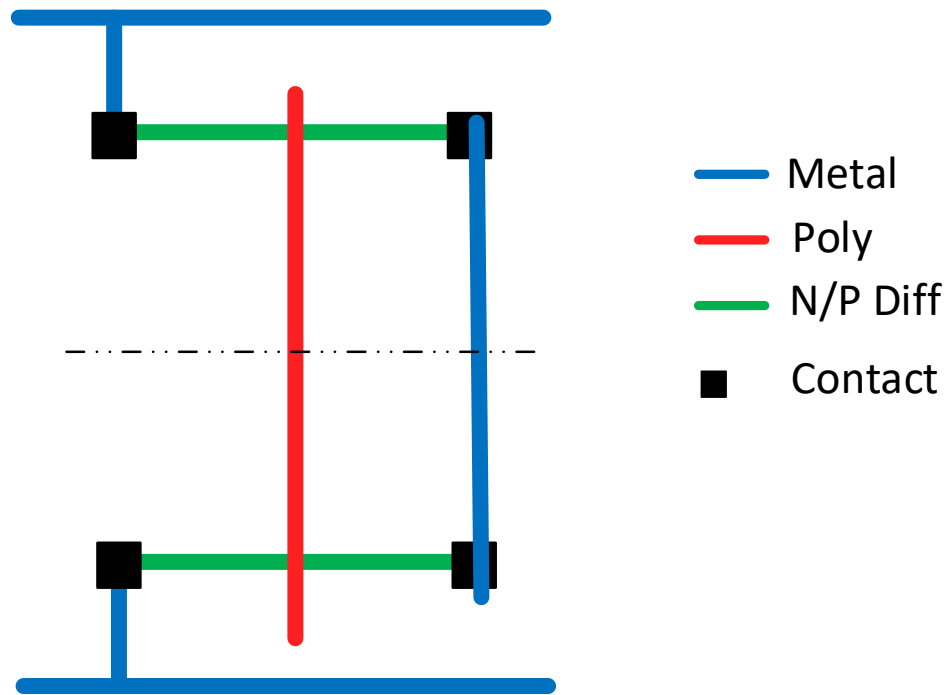
- Read-in schematic netlist
- Generate internal graph representation
- Reduce (if directed) parallel, series components
- Read-in layout netlist (as a gdsII file)
- Use geometry and layer rules (specified in your calibre.lvs file) to generate graph representation
- Reduce if necessary
- Perform equivalence checking between the 2 graphs
- If check fails, report the points of mismatch (careful here!)



Source: Ling,  
IBM

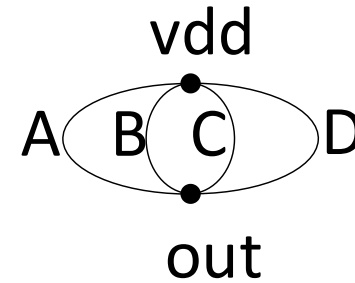
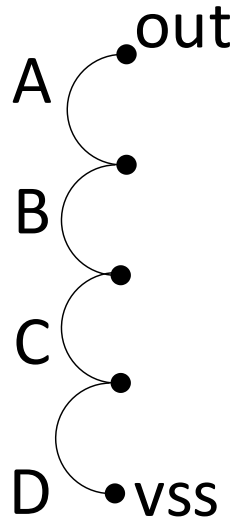
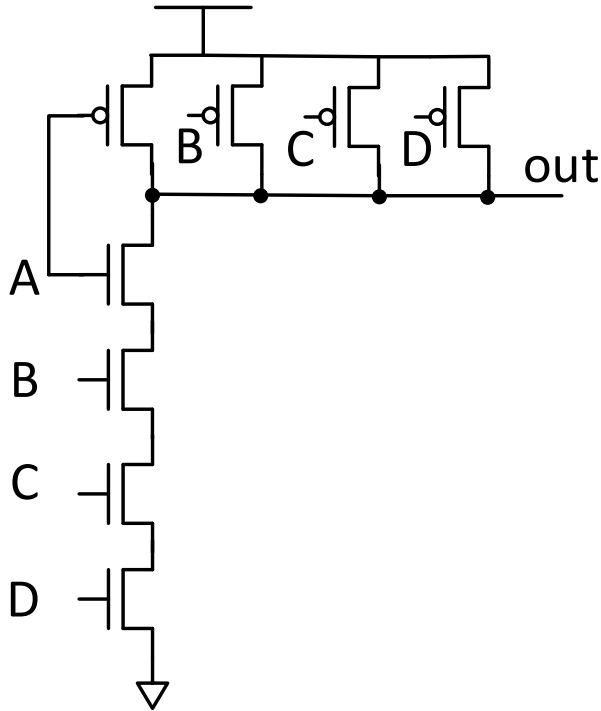


# Stick Diagrams: A Quick Introduction



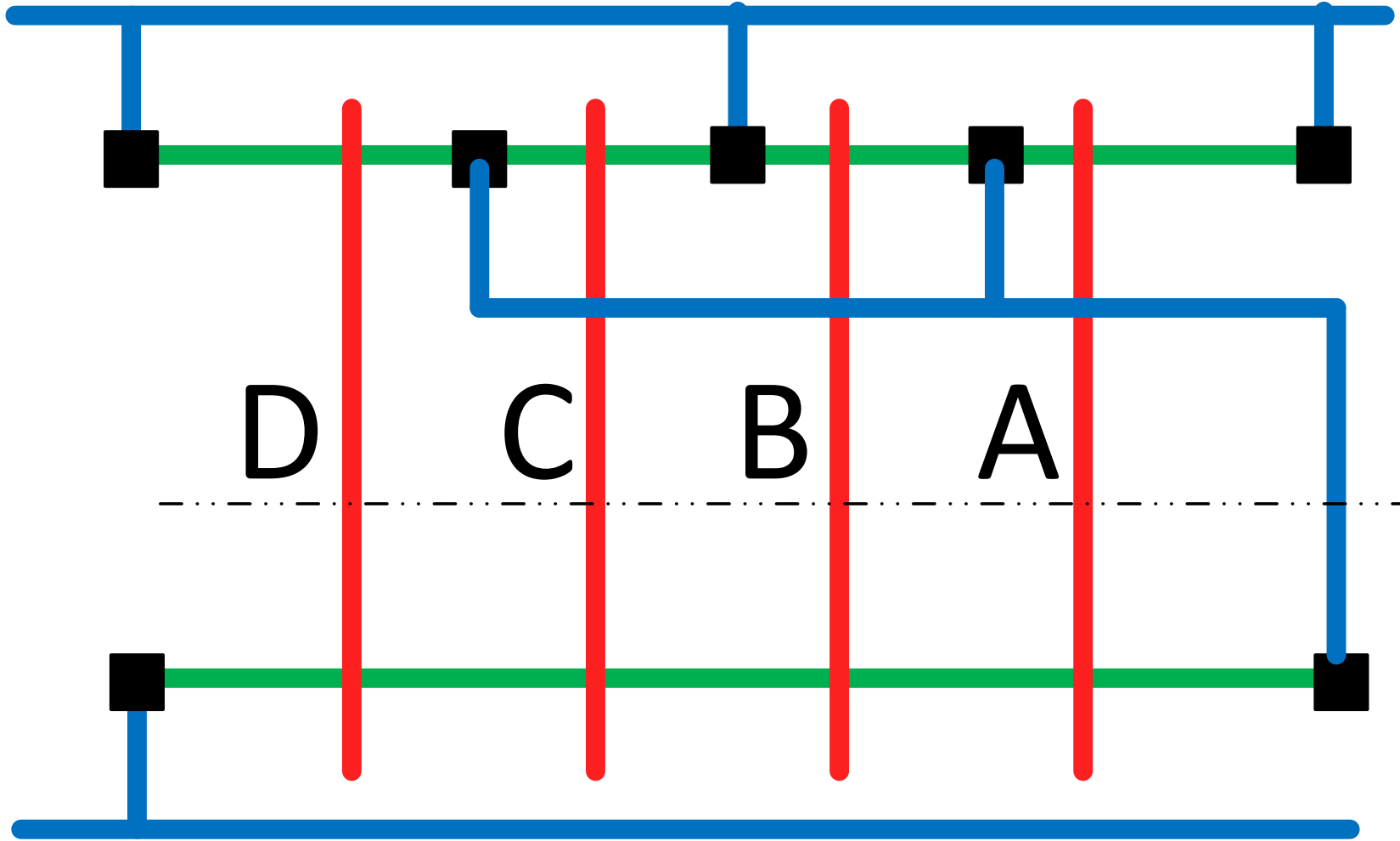
- Moderately complex CMOS gates have non-unique (and other inefficient) ways of being built
- An informal means to sketch out and plan your layout ahead of time
- Part of required reading: W&H Section 1.5.5 (2 pages)

# Parting notes on efficient layout: Euler Paths

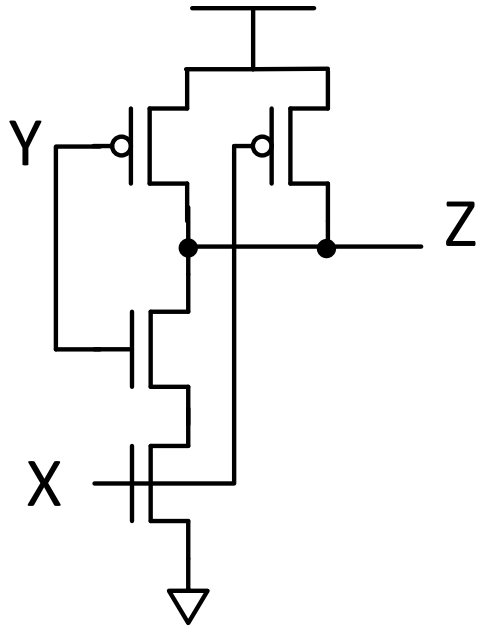


- Euler path: A traversal of a graph which visits **every** edge exactly once
- Draw the pullup/pulldown graph (or sub-graph) and identify an euler path
- Identify whether the dual graph has an euler path with the same path sequence. If yes, gate connections are made a lot simpler

# Leveraging Dual Eulerian Graphs

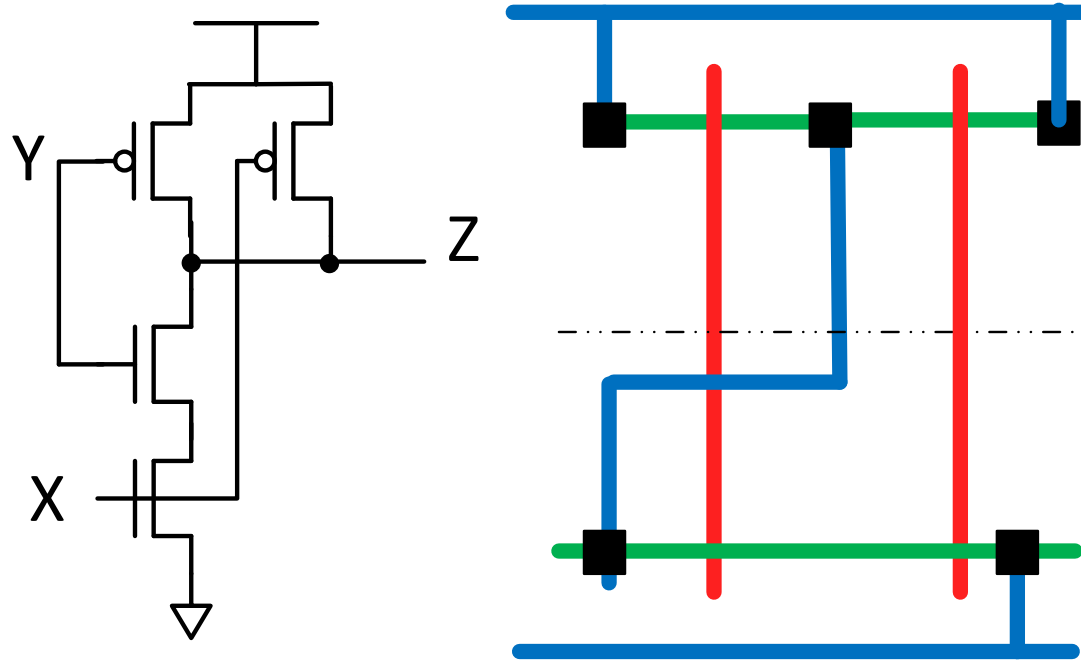


# Parting notes on efficient layout: Drain Sharing



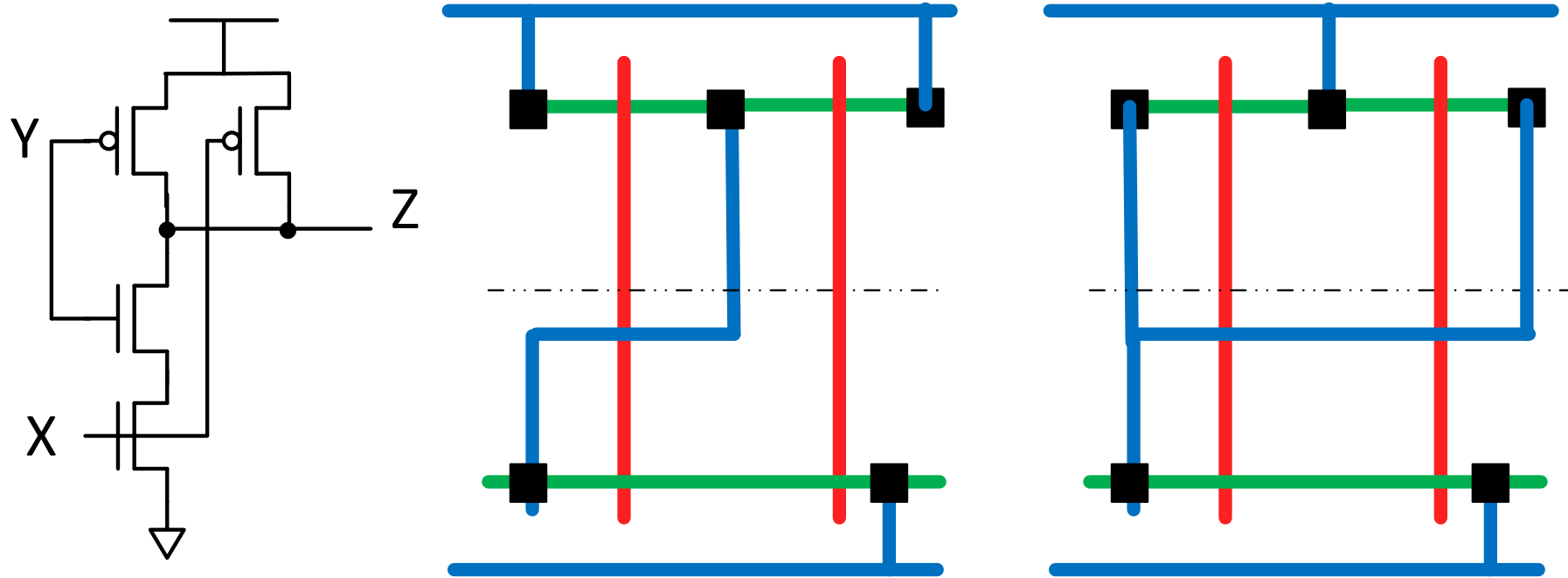
- Effective means to reduce the parasitic junction, and wiring capacitance
- Use stick diagrams to plan layout accordingly

# Parting notes on efficient layout: Drain Sharing



- Effective means to reduce the parasitic junction, and wiring capacitance
- Use stick diagrams to plan layout accordingly

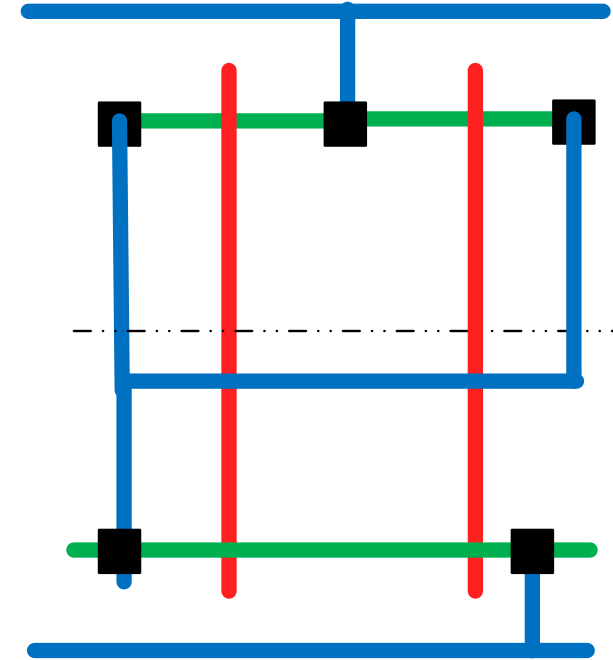
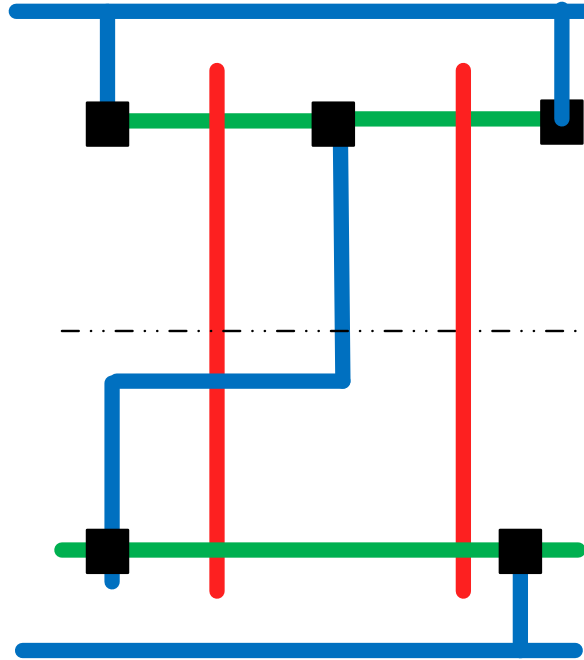
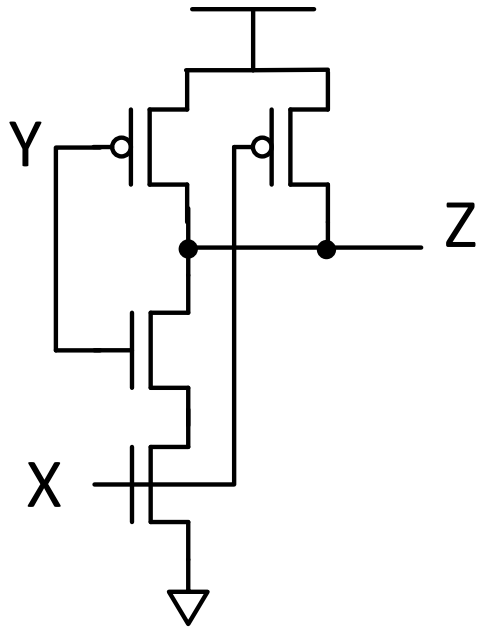
# Parting notes on efficient layout: Drain Sharing



- Effective means to reduce the parasitic junction, and wiring capacitance
- Use stick diagrams to plan layout accordingly



# Parting notes on efficient layout: Drain Sharing



OK. Given a choice,  
which is better layout?



- Effective means to reduce the parasitic junction, and wiring capacitance
- Use stick diagrams to plan layout accordingly

# Reading assignment

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- Required reading
  - W&H Section 1.5\*
- Optional Reading
  - W&H Chapter 3